



**UNIVERSITÉ
DE GENÈVE**

FACULTÉ DES SCIENCES

Département de physique
nucléaire et corpusculaire



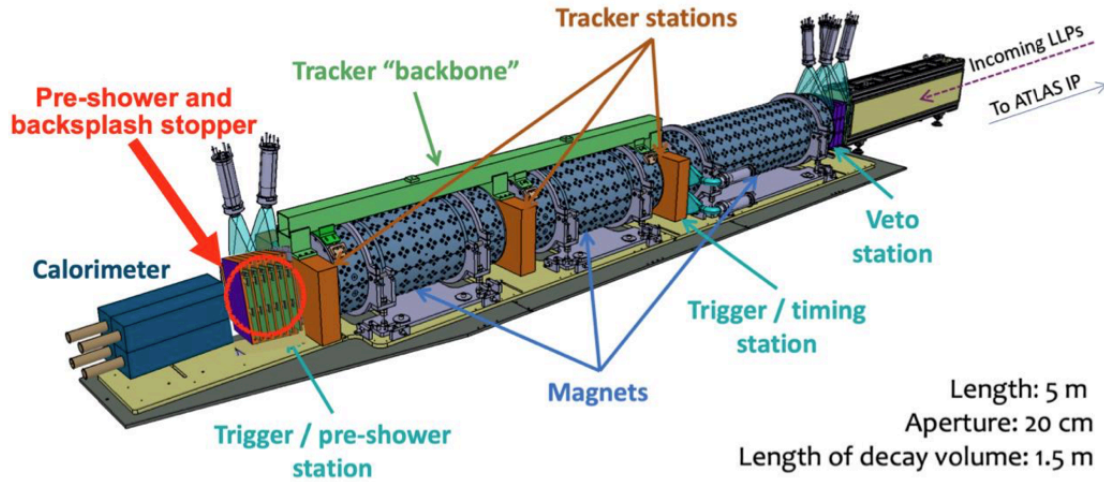
The Monolithic ASIC for the High Precision Preshower Detector of the FASER Experiment at the LHC

CHIARA MAGLIOCCA

on behalf of the FASER Preshower Upgrade Team

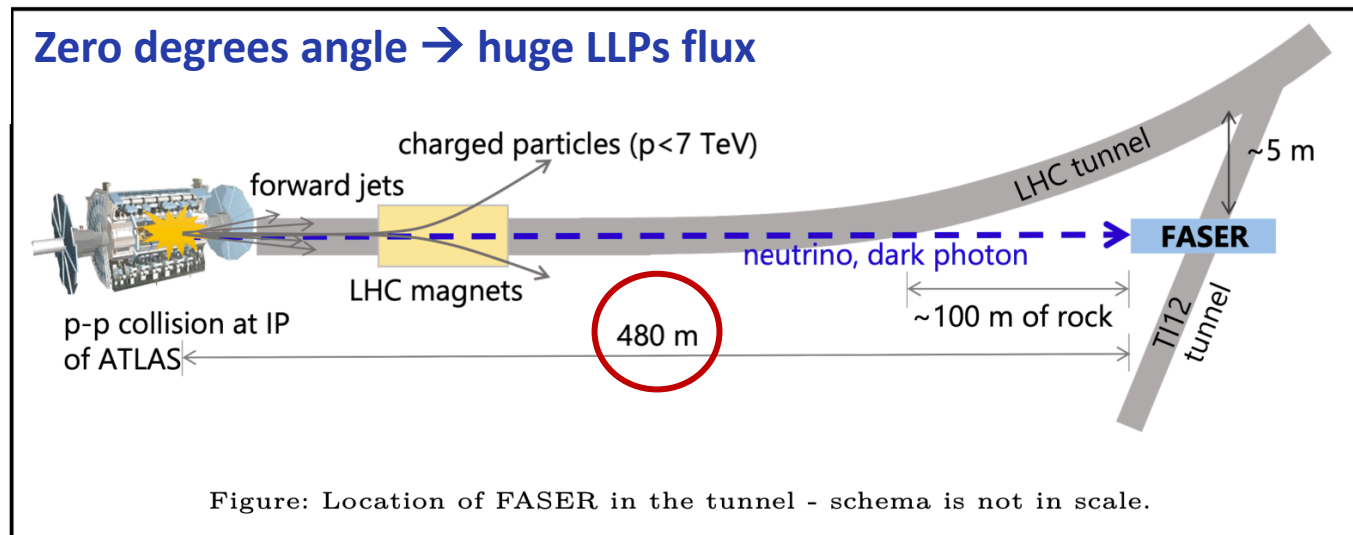
Joint SPS and ÖPG Annual Meeting 2023, Basel

The FASER Experiment at LHC

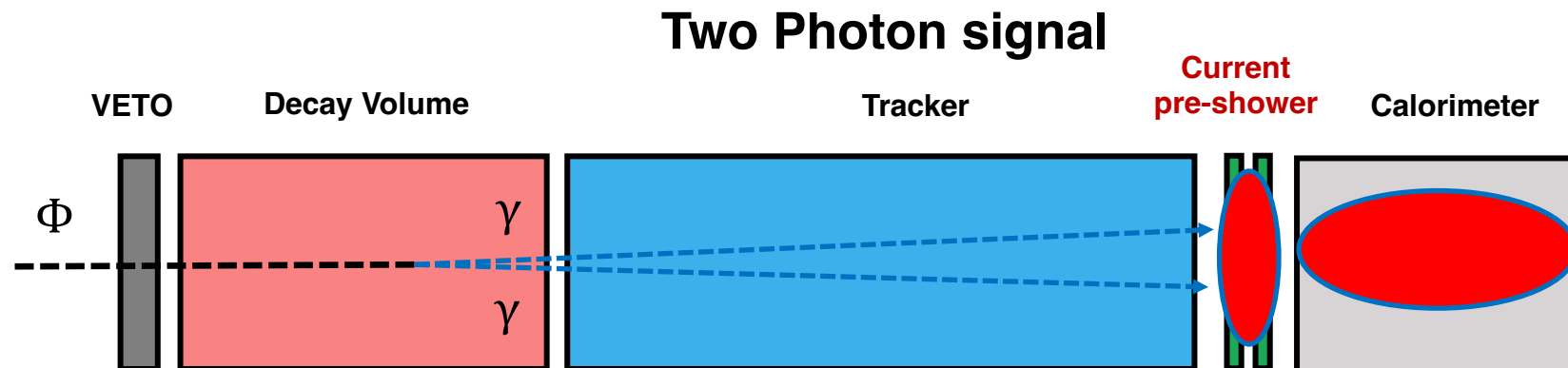
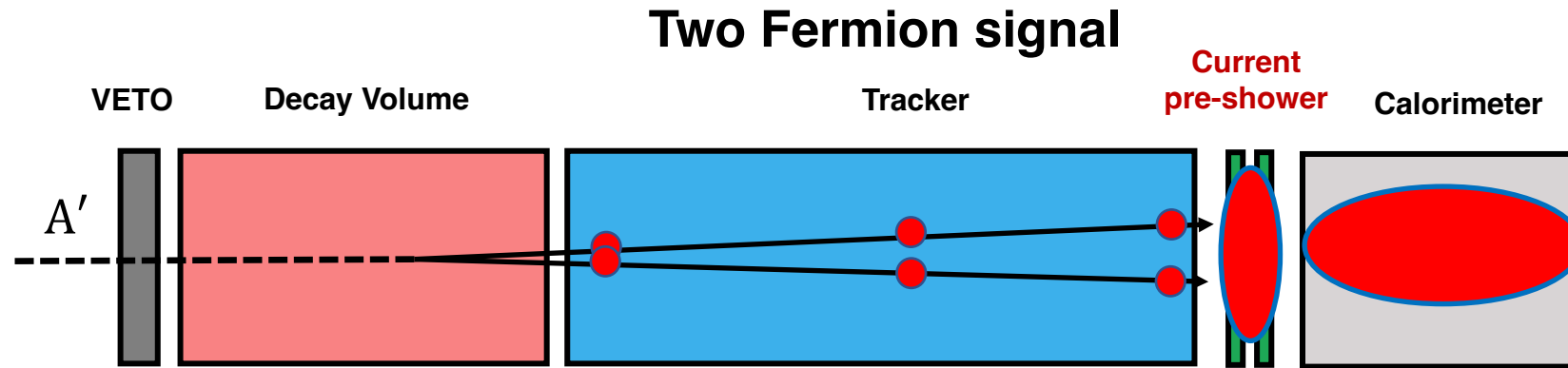


- ForwArd Search ExpeRiment
- Designed to search for **light and weakly-interacting particles** + study the **interactions of high-energy neutrinos** (FaserNu)

- Fluxes of high-energy SM particles are suppressed
- Muons and neutrinos only exception
- FASER can probe **Axion-Like-Particles** (ALPs) model



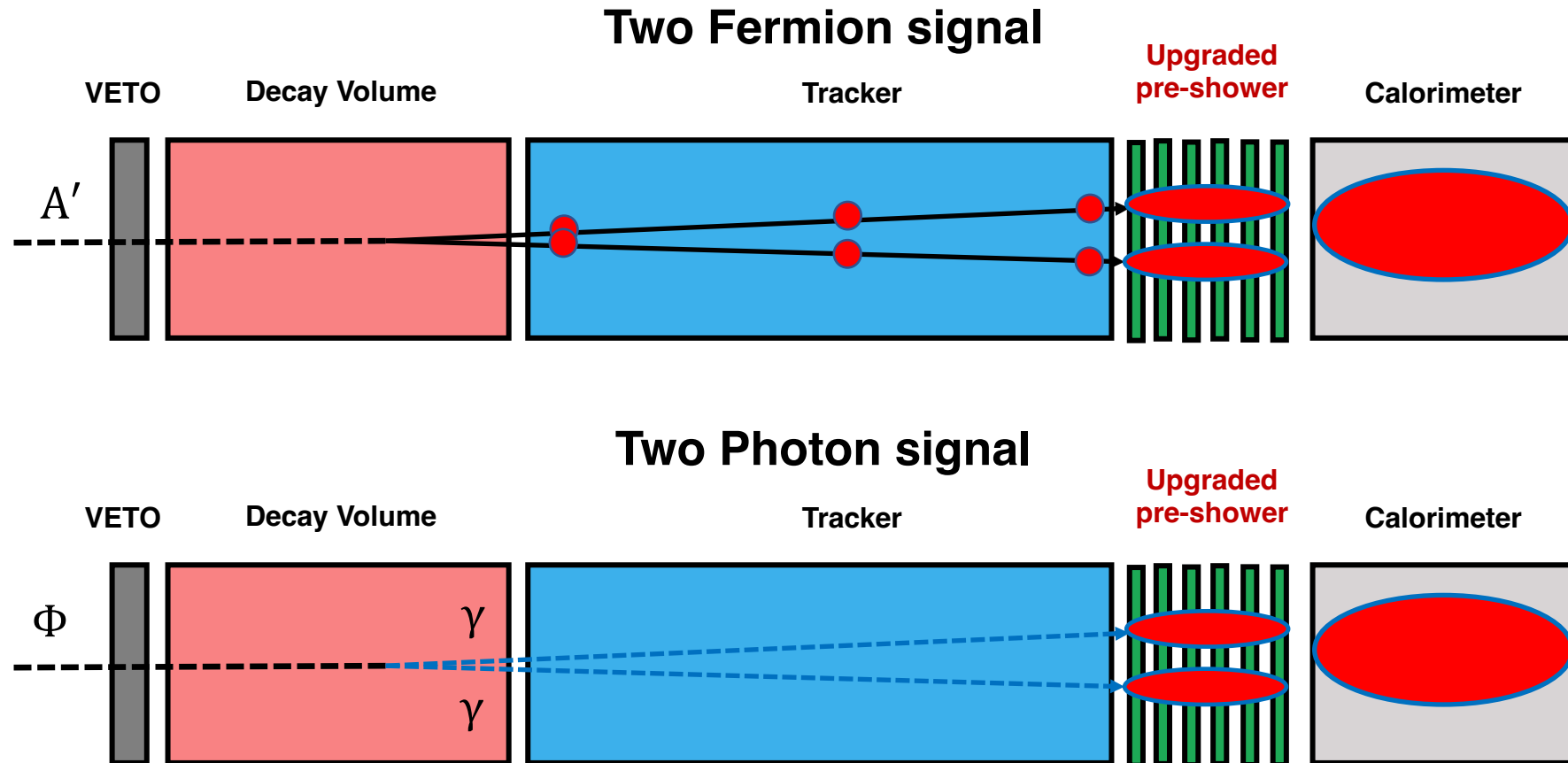
What Are We Able to Detect Well: Two Fermion Signal



NO XY GRANULARITY

unable to resolve diphoton events!

What Are We Willing to Detect: Two Photon Signal



HIGH XY GRANULARITY

The FASER Pre-shower Detector Upgrade

Main Challenge:
Independent measurement of two very collimated
high energy photons

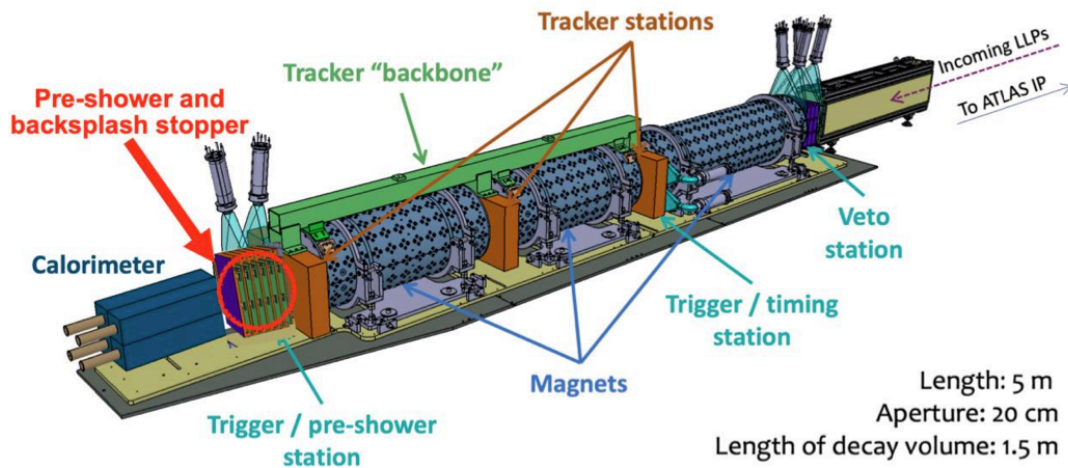
Current preshower:

2 layers of tungsten (1X0) + scintillating detectors

→ no XY granularity

The upgrade:

- **High granularity/high dynamic range** pre-shower based on monolithic silicon pixels sensors
- Discriminate **TeV scale electromagnetic showers**
- Targeting data-taking during last year of LHC Run 3 and HL-LHC

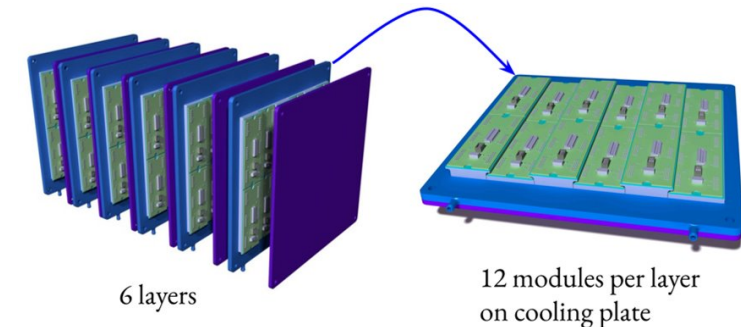
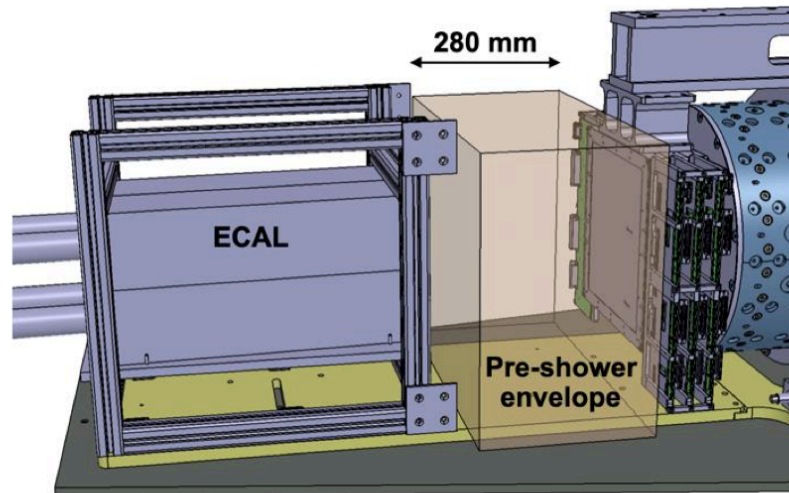
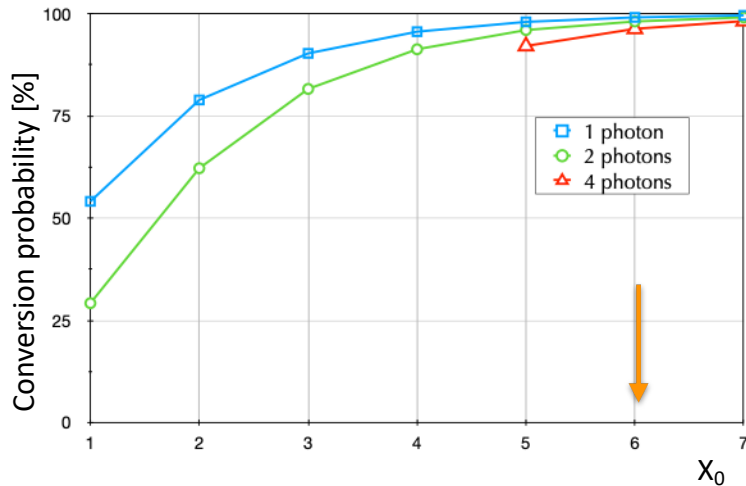
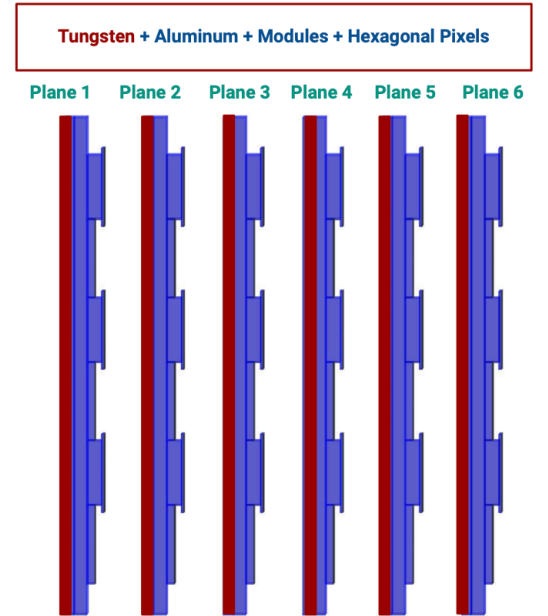


Pre-shower Upgrade Design

- 6 detector planes
- $6X_0$ of tungsten in total
- One plane of monolithic Si-pixel sensors after each tungsten layer

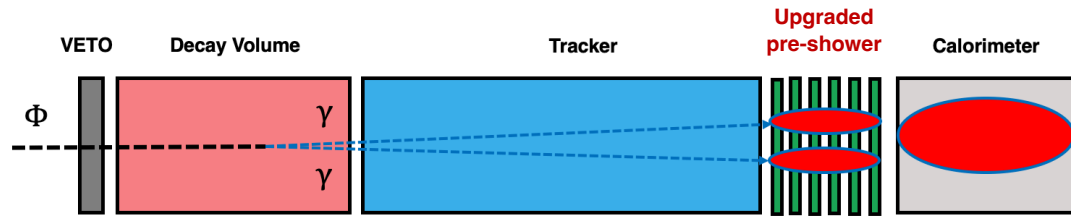
$$2 * (1.70 X_0 \text{ of W + Si plane}) + 4 * (0.65 X_0 \text{ of W + Si plane})$$

More tungsten in the first two layers to force early photon conversion


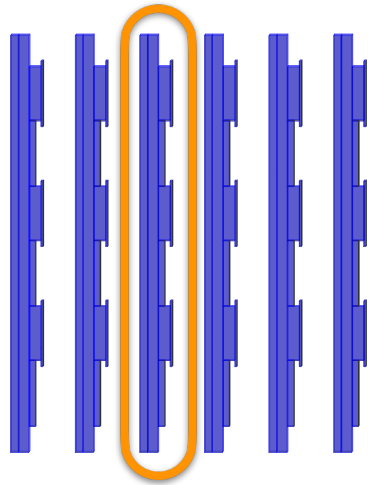


Pre-shower Simulation: Diphoton Signature

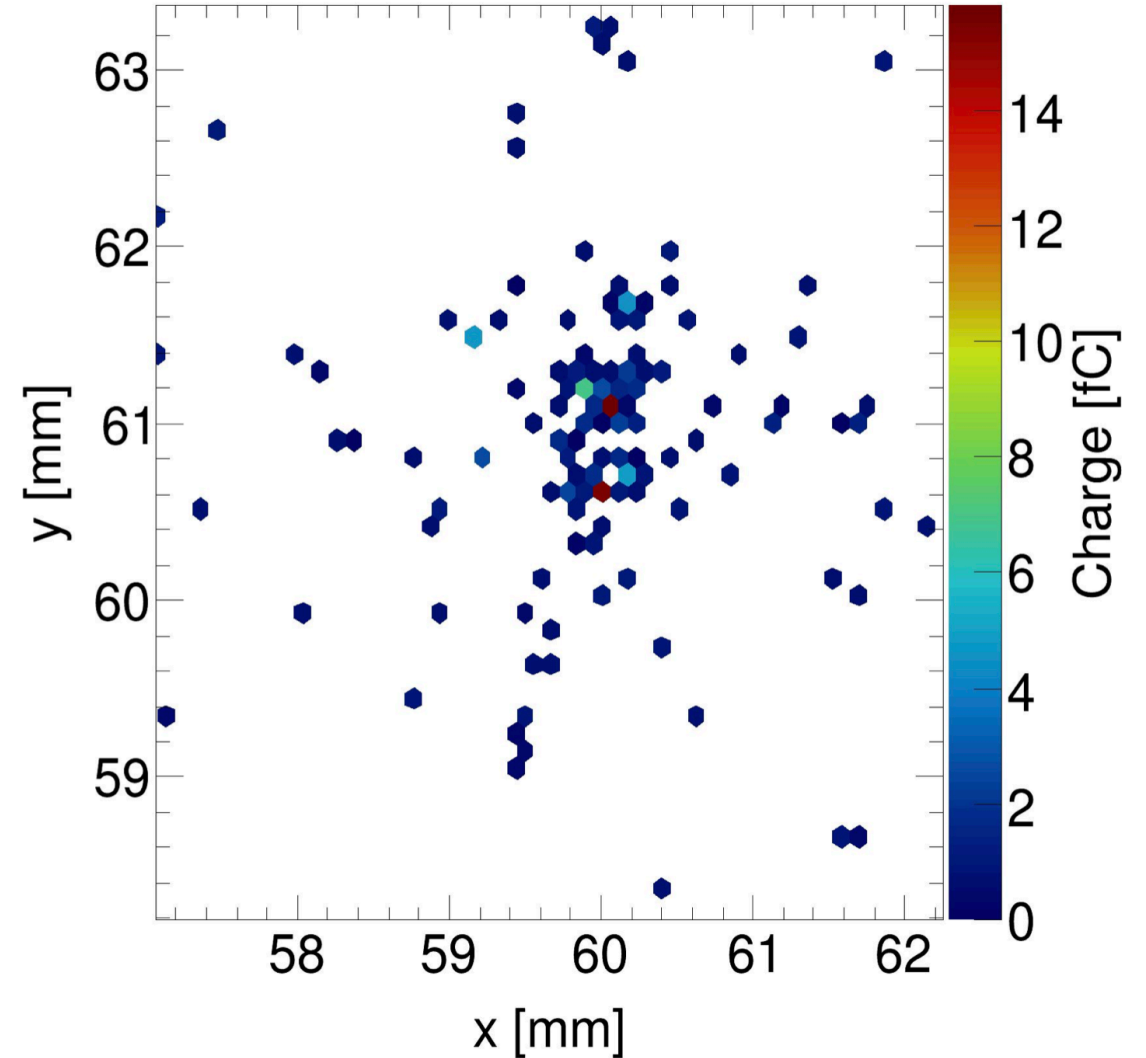
Why 6 planes?
Why pixelated sensors?



E1= 1 TeV
E2= 1 TeV
d=500um

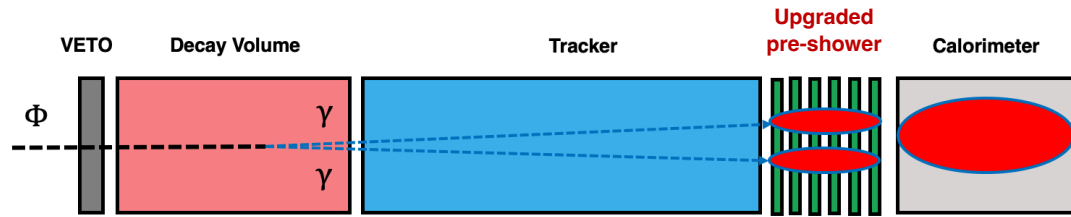



Layer 3


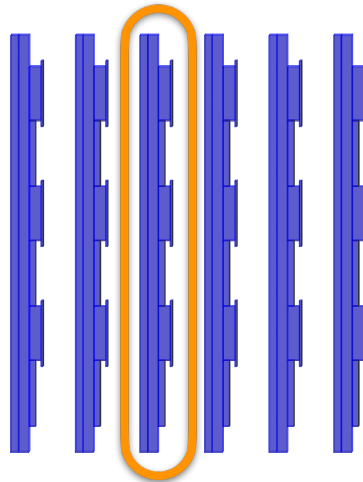


Pre-shower Simulation: Diphoton Signature

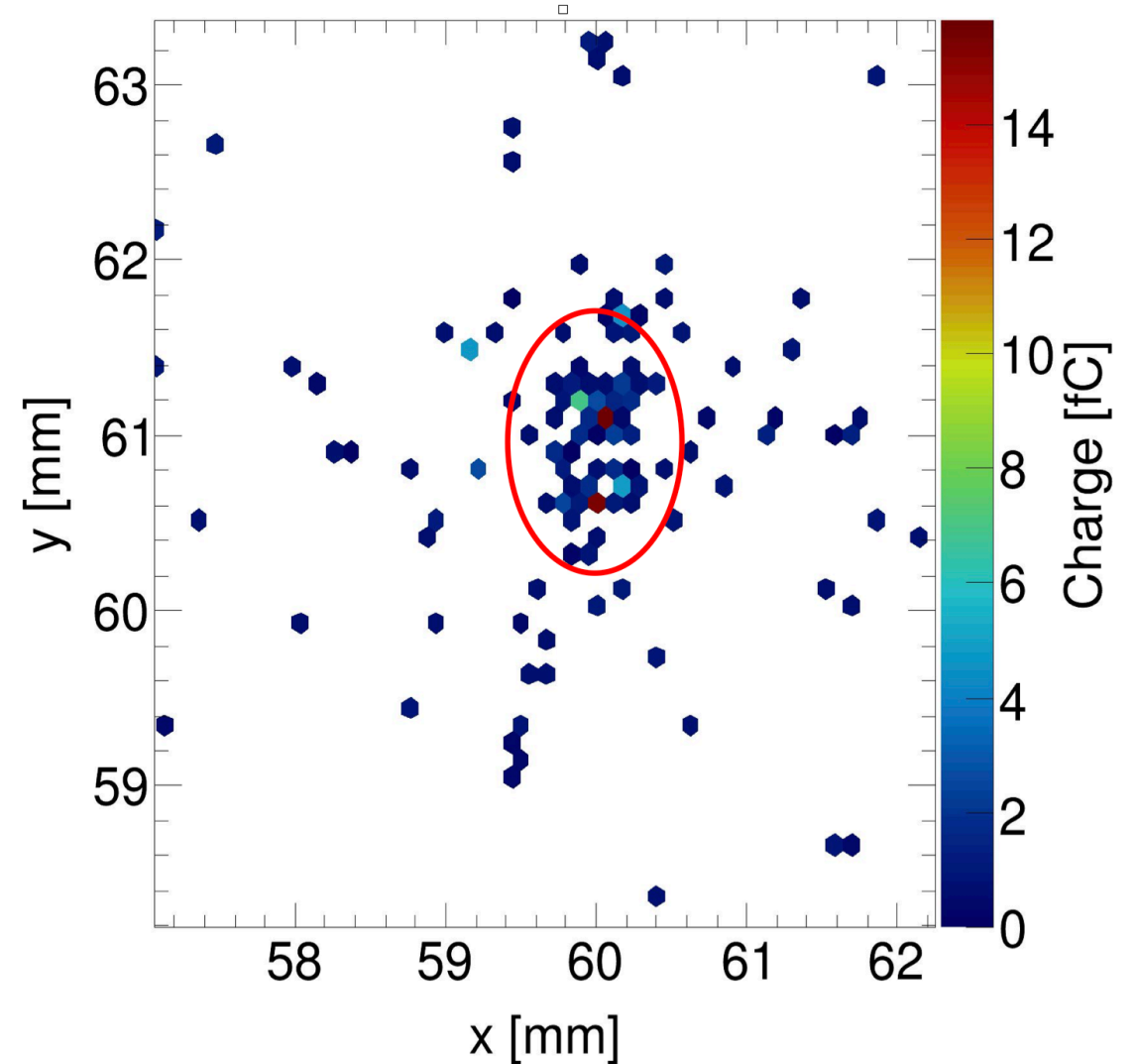
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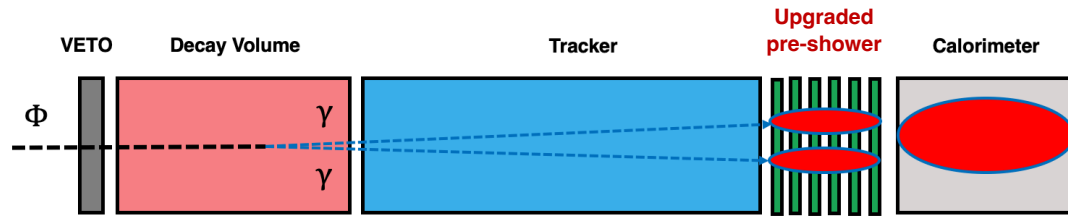



Layer 3

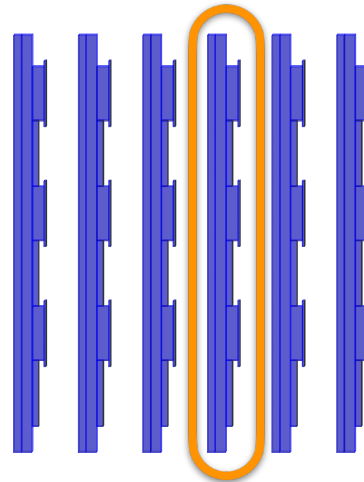


Pre-shower Simulation: Diphoton Signature

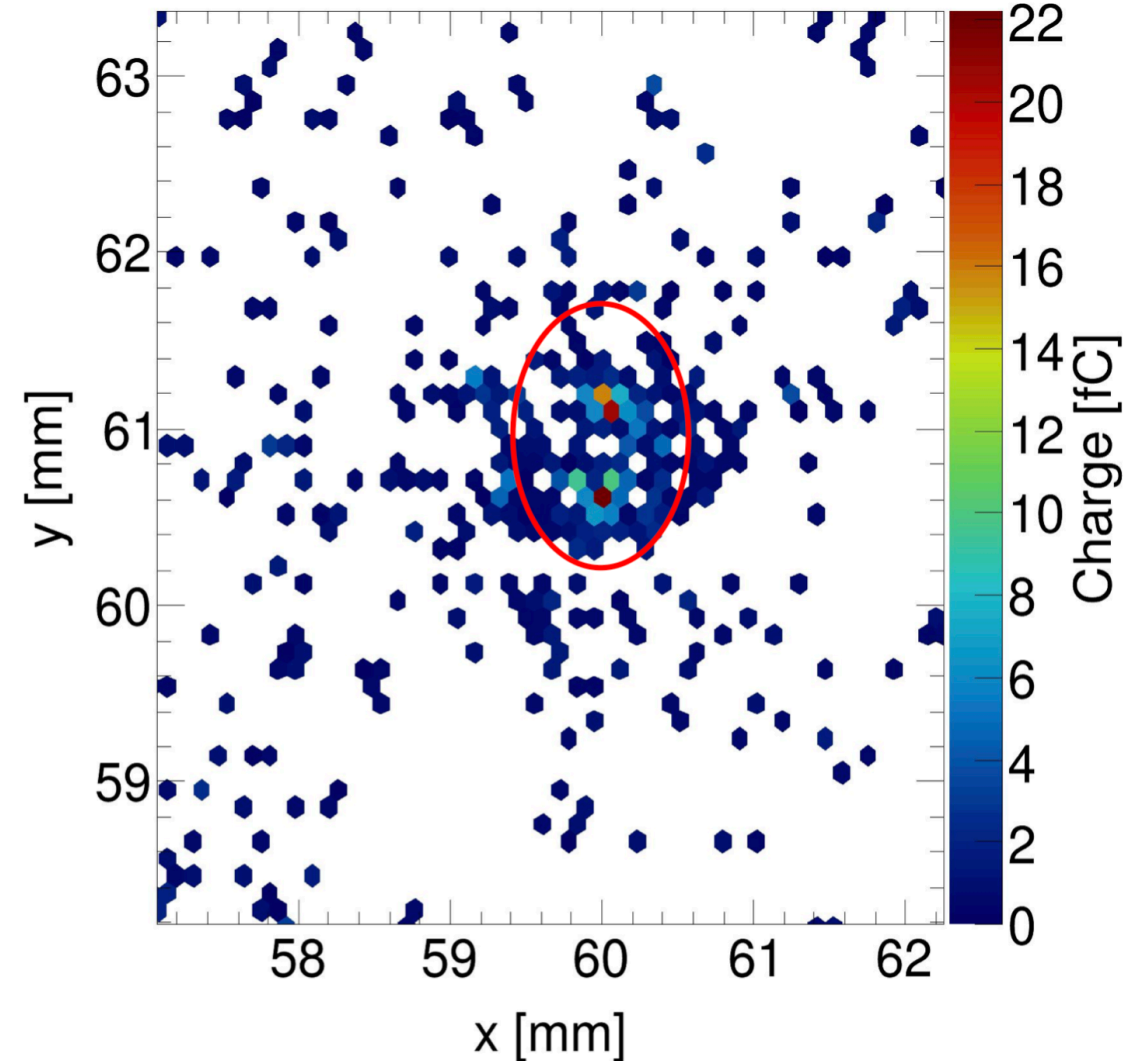
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Why pixelated sensors?



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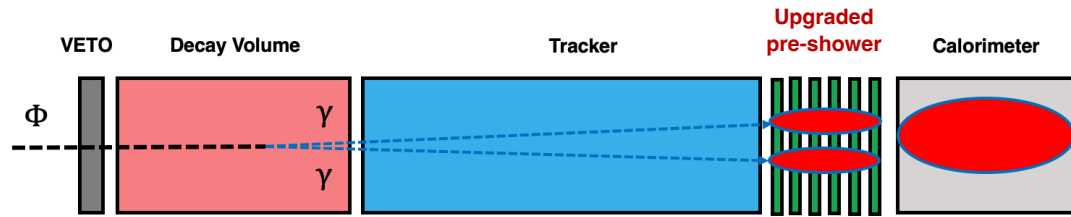



Layer 4


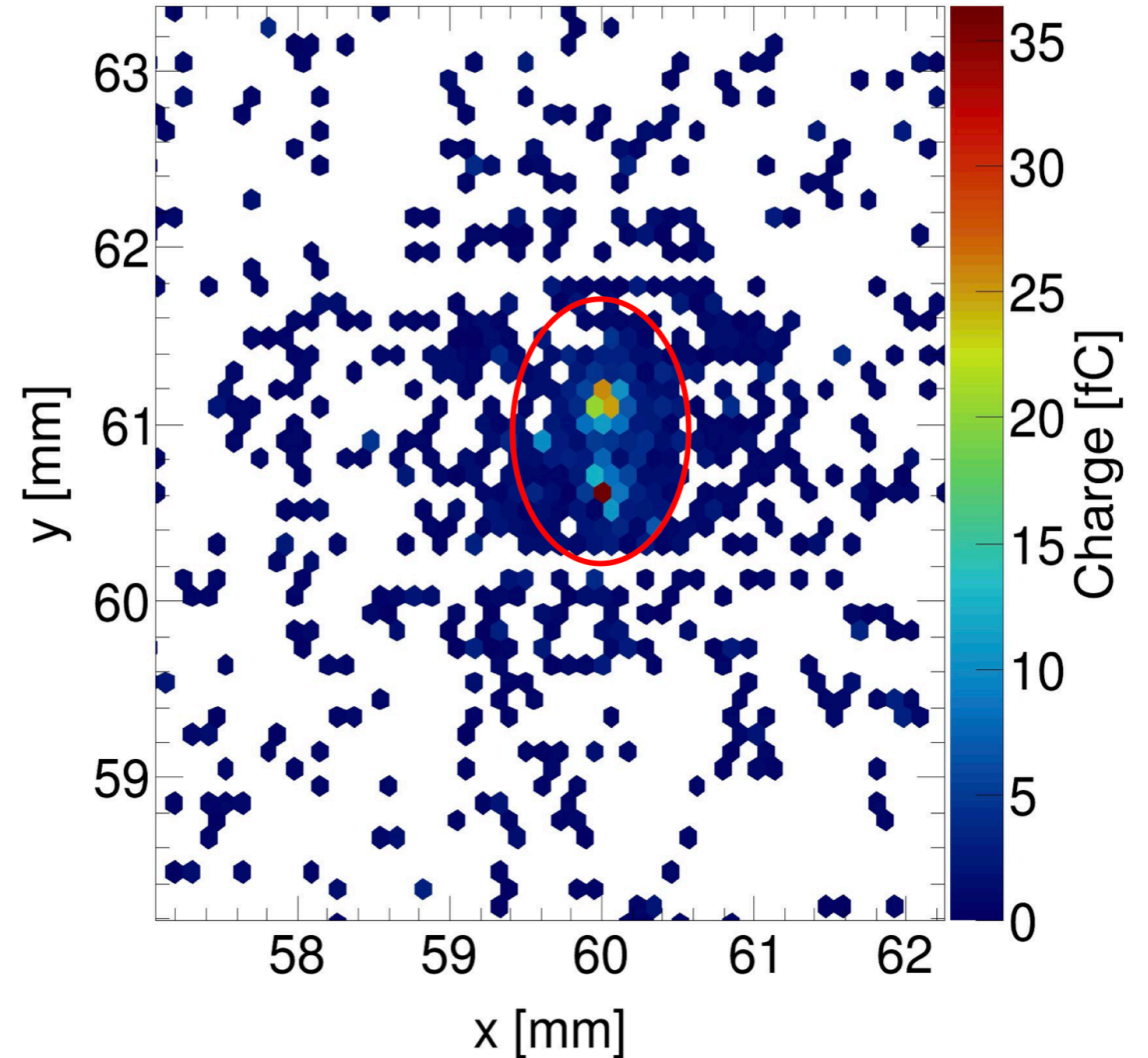
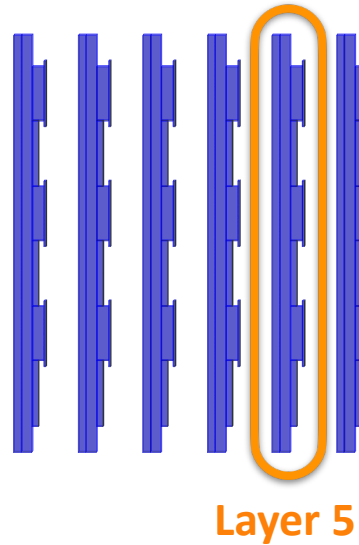


Pre-shower Simulation: Diphoton Signature

Why 6 planes?
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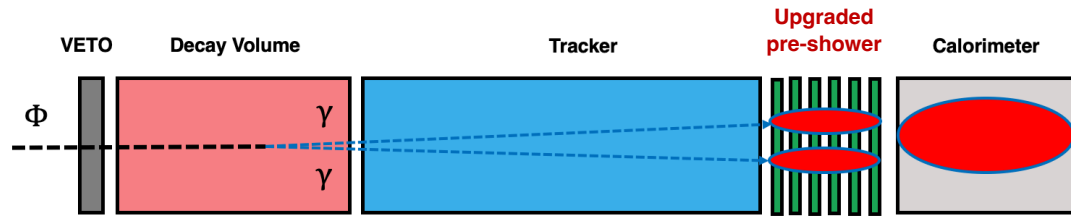


E1 = 1 TeV
E2 = 1 TeV
d = 500 μ m

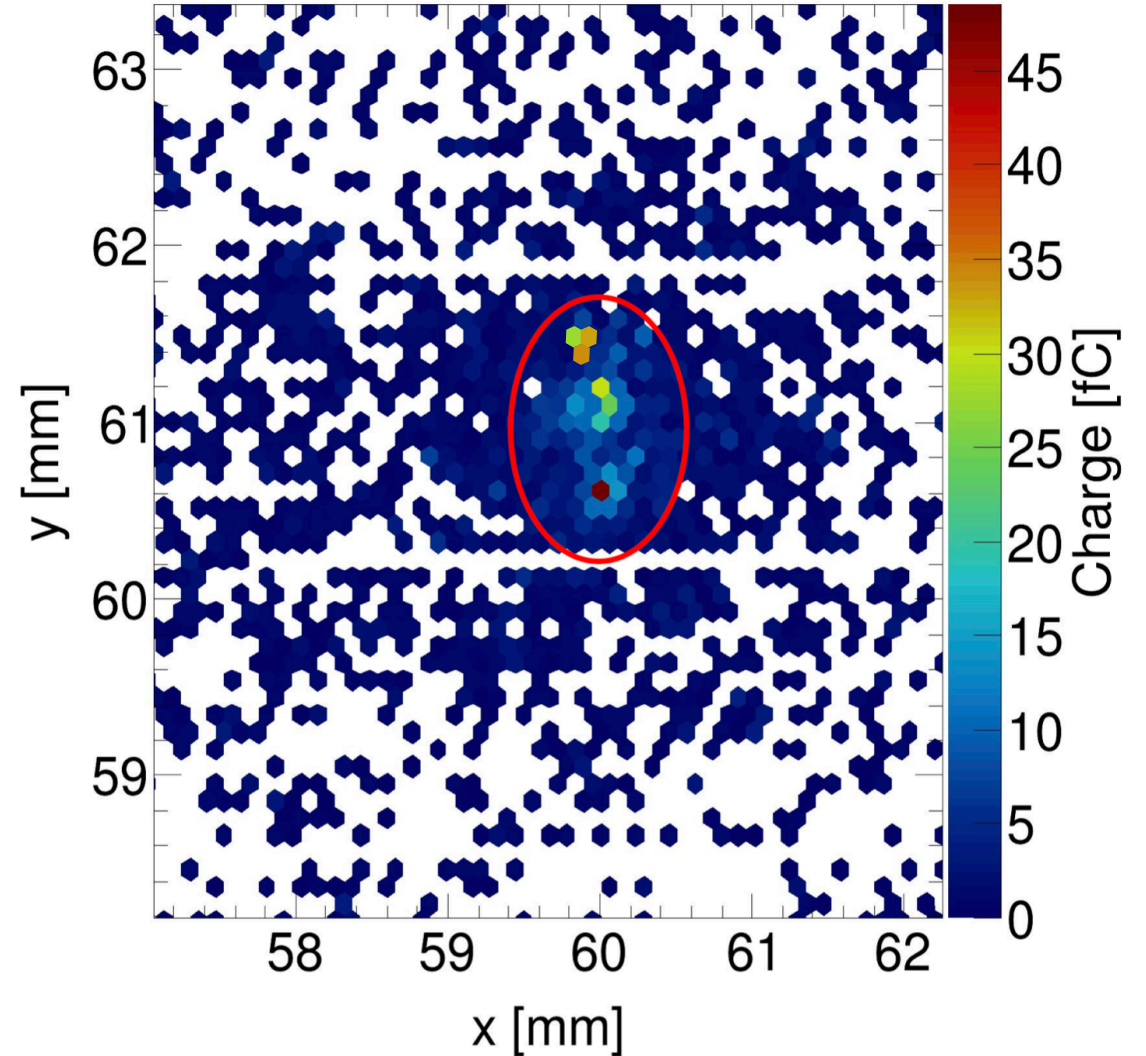
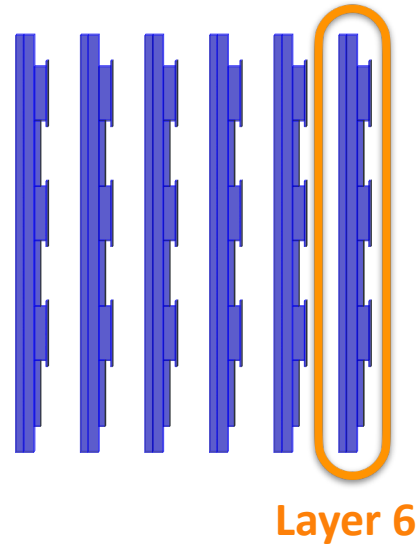



Pre-shower Simulation: Diphoton Signature

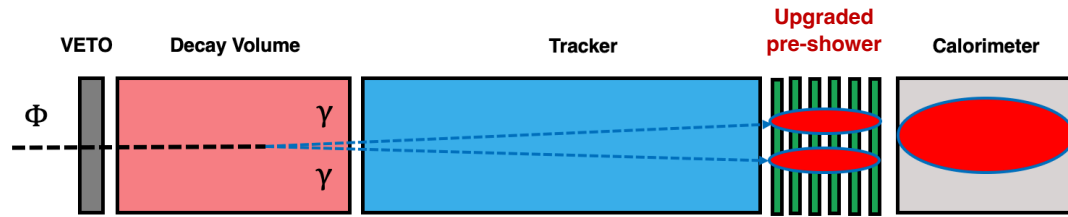
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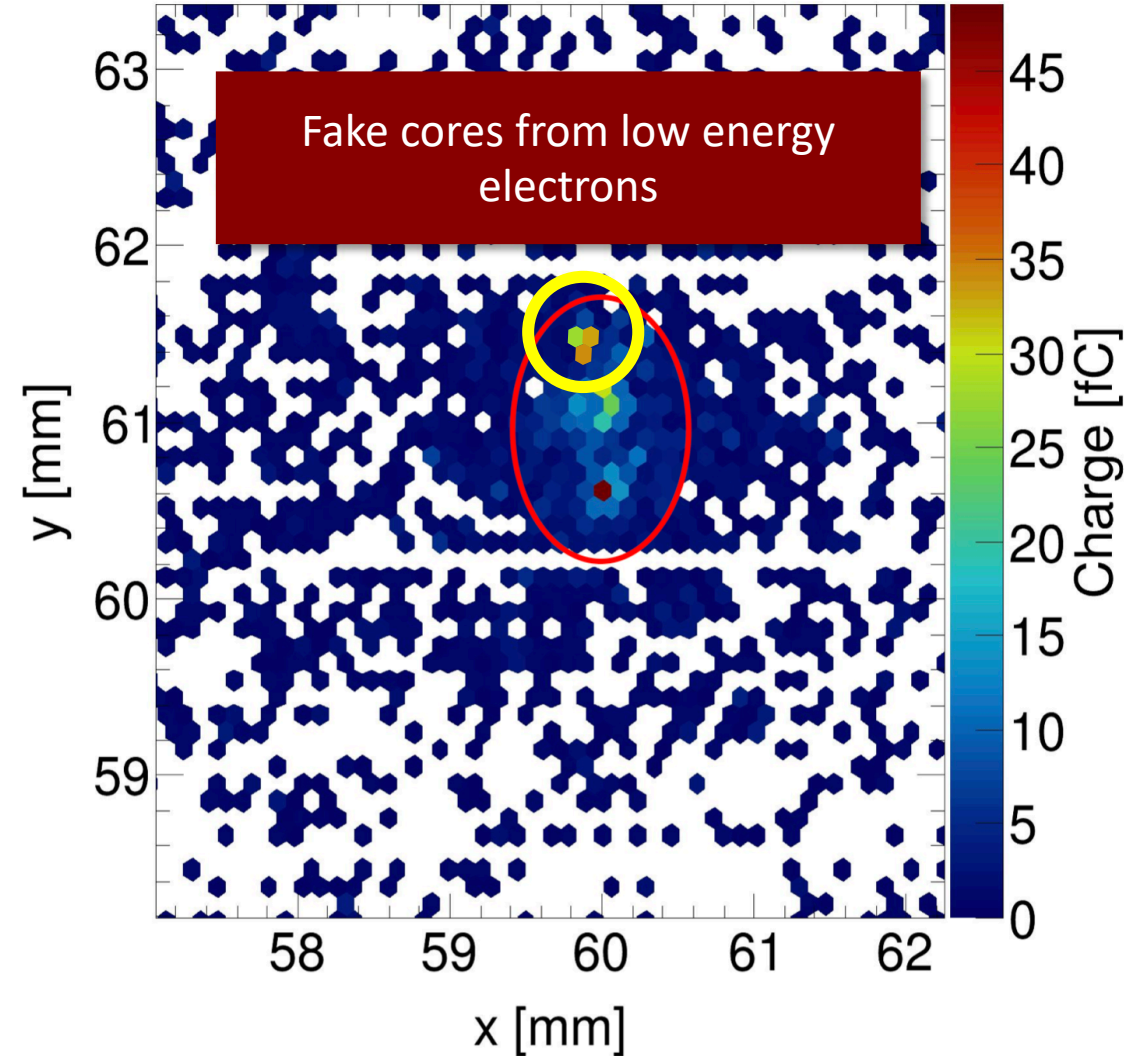
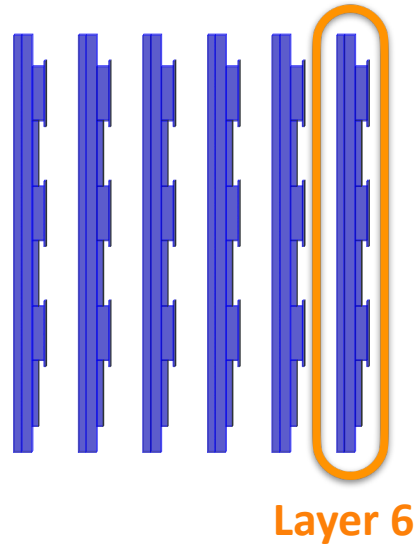
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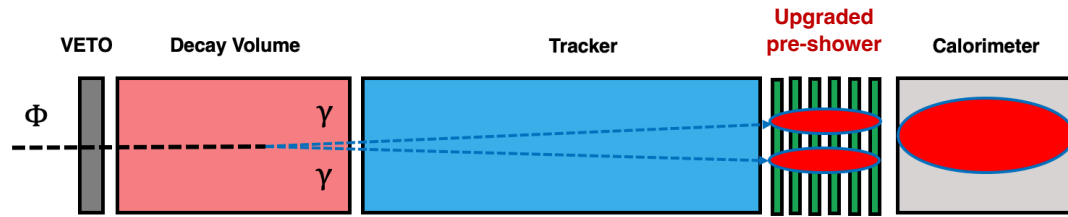
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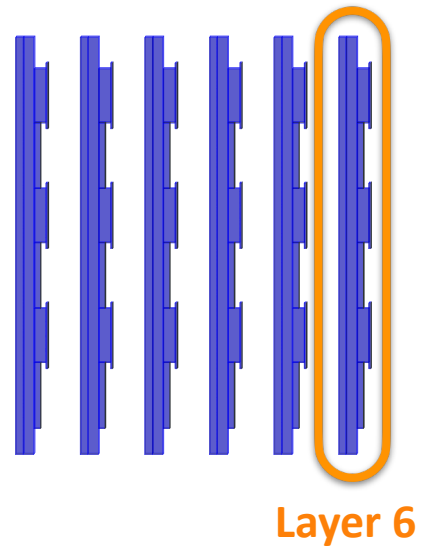
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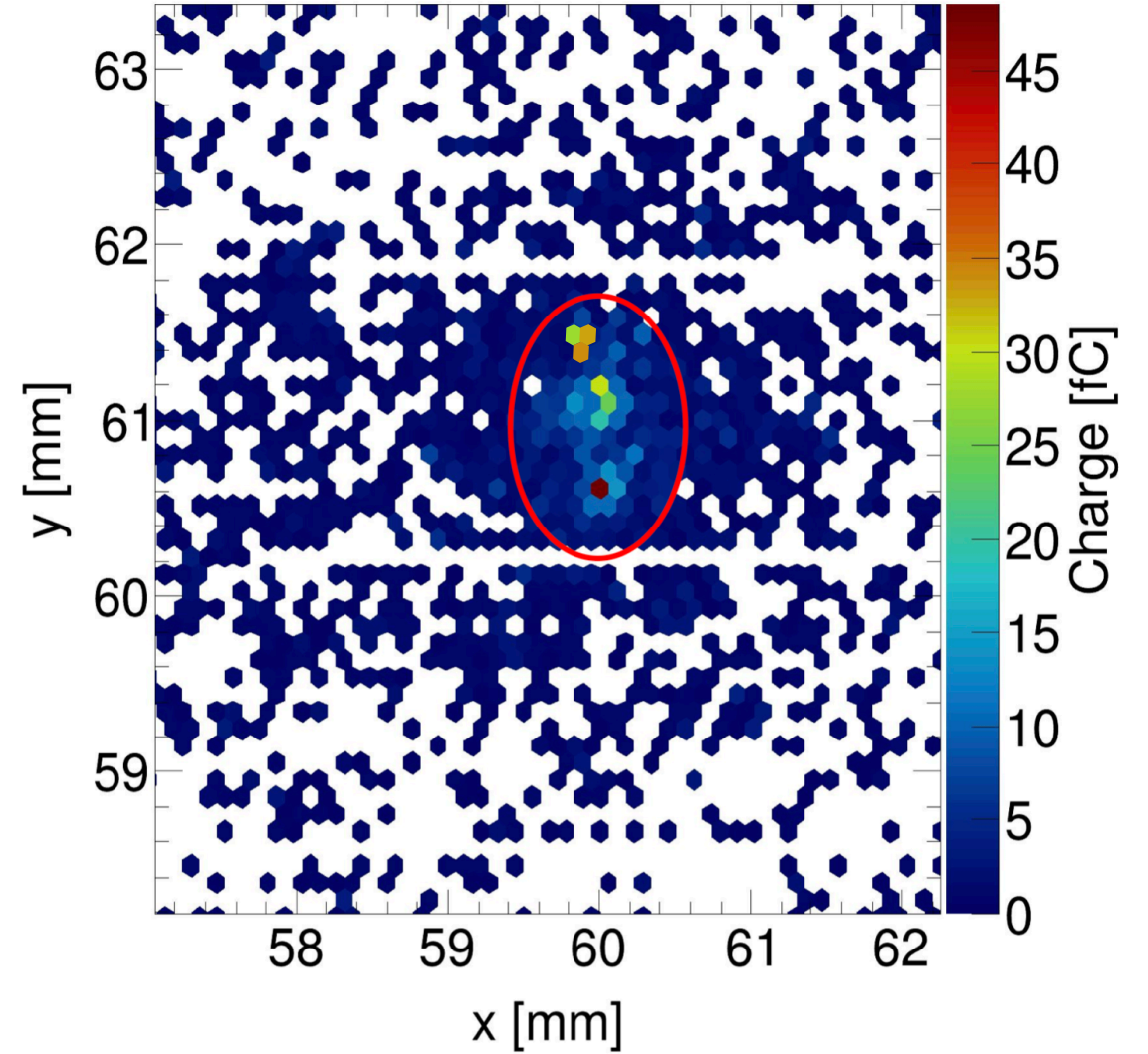


E1= 1 TeV
E2= 1 TeV
d=500um

Very large occupancy

High dynamic range for charge measurements



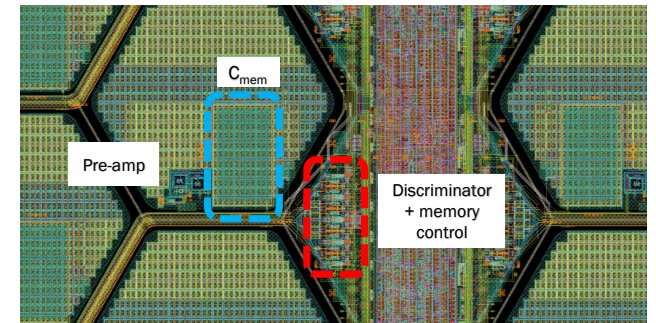
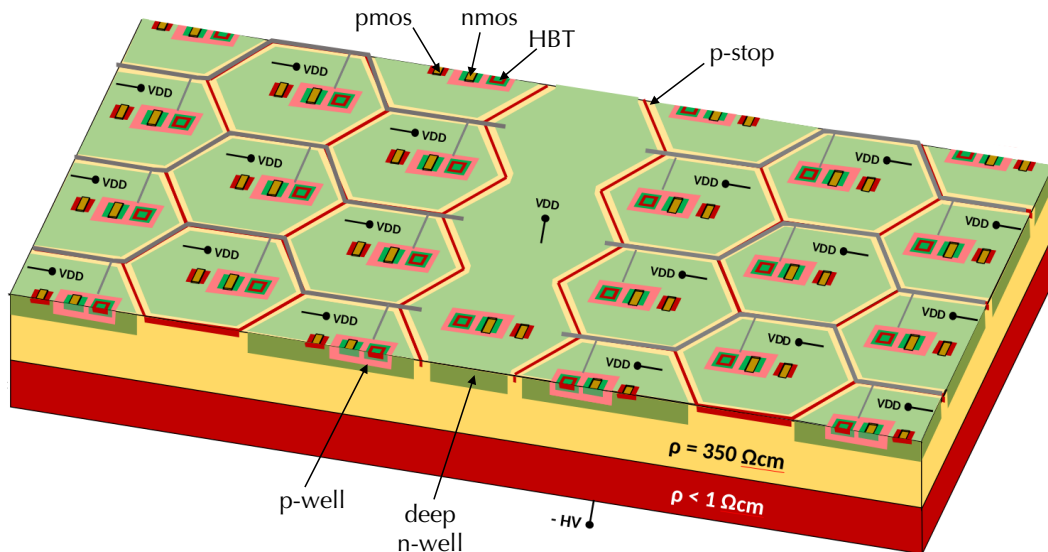
Monolithic Pixel ASIC: the Sensor



Monolithic active pixel sensor

130 nm SiGe BiCMOS technology (SG13G2 by IHP microelectronics)

- High-resistivity ($220 \Omega\text{cm}$) substrate, about $130 \mu\text{m}$ thickness
- Hexagonal $65 \mu\text{m}$ side pixels integrated as triple well; 80fF pixel capacitance
- **High dynamic range** for charge measurement ($0.5 \div 65 \text{ fC}$)
- **Ultra fast readout** with no digital memory on-chip (to minimize dead area)
- **Local analog memories** to store the charge



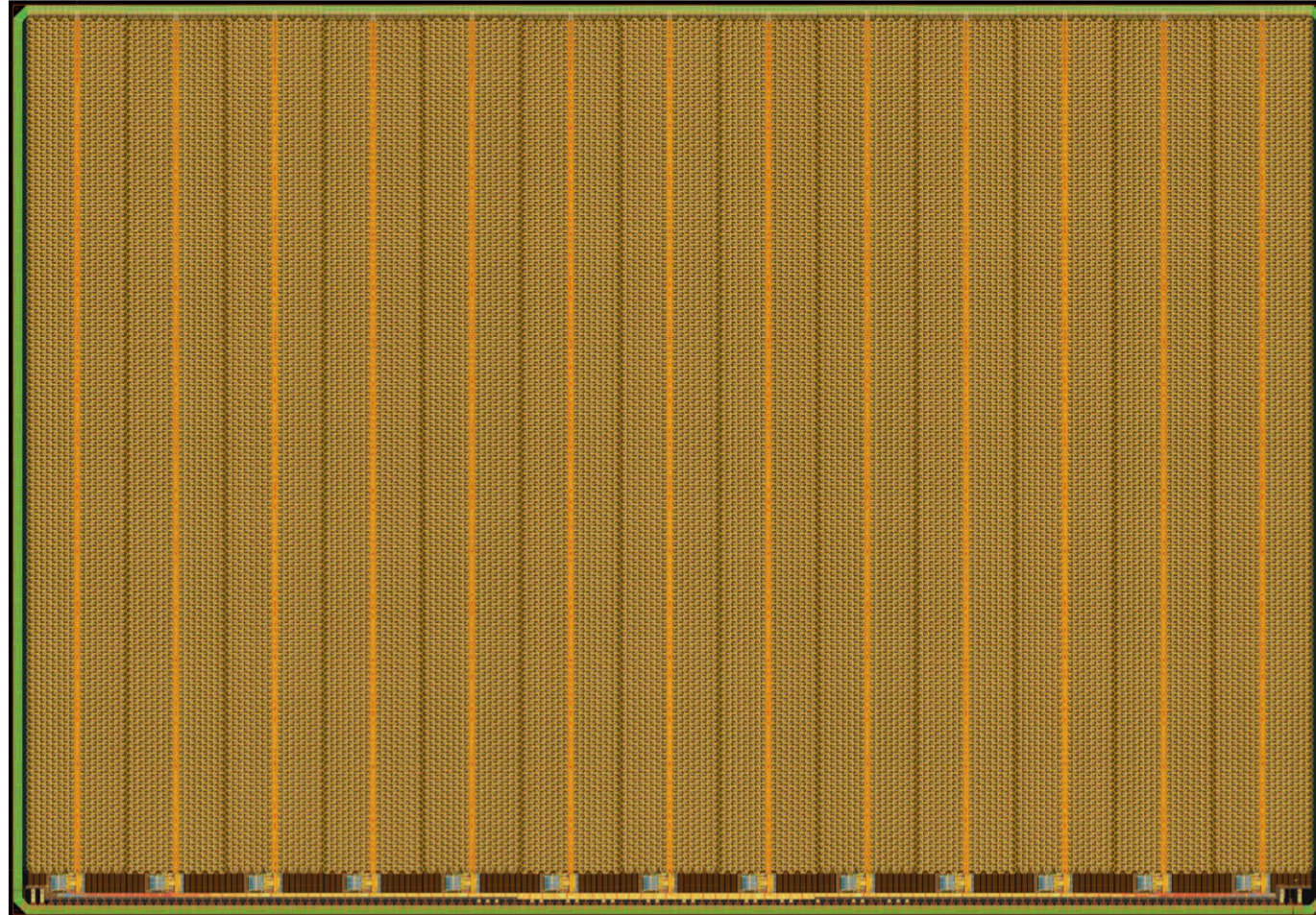
Main specifications	
Pixel Size	$65 \mu\text{m}$ side (hexagonal)
Pixel dynamic range	$0.5 \div 65 \text{ fC}$
Cluster size	$O(1000)$ pixels
Readout time	$< 200 \mu\text{s}$
Power consumption	$< 150 \text{ mW/cm}^2$
Time resolution	$< 300 \text{ ps}$

Final Production Chip submitted in May 2023

Monolithic ASIC Modular Architecture



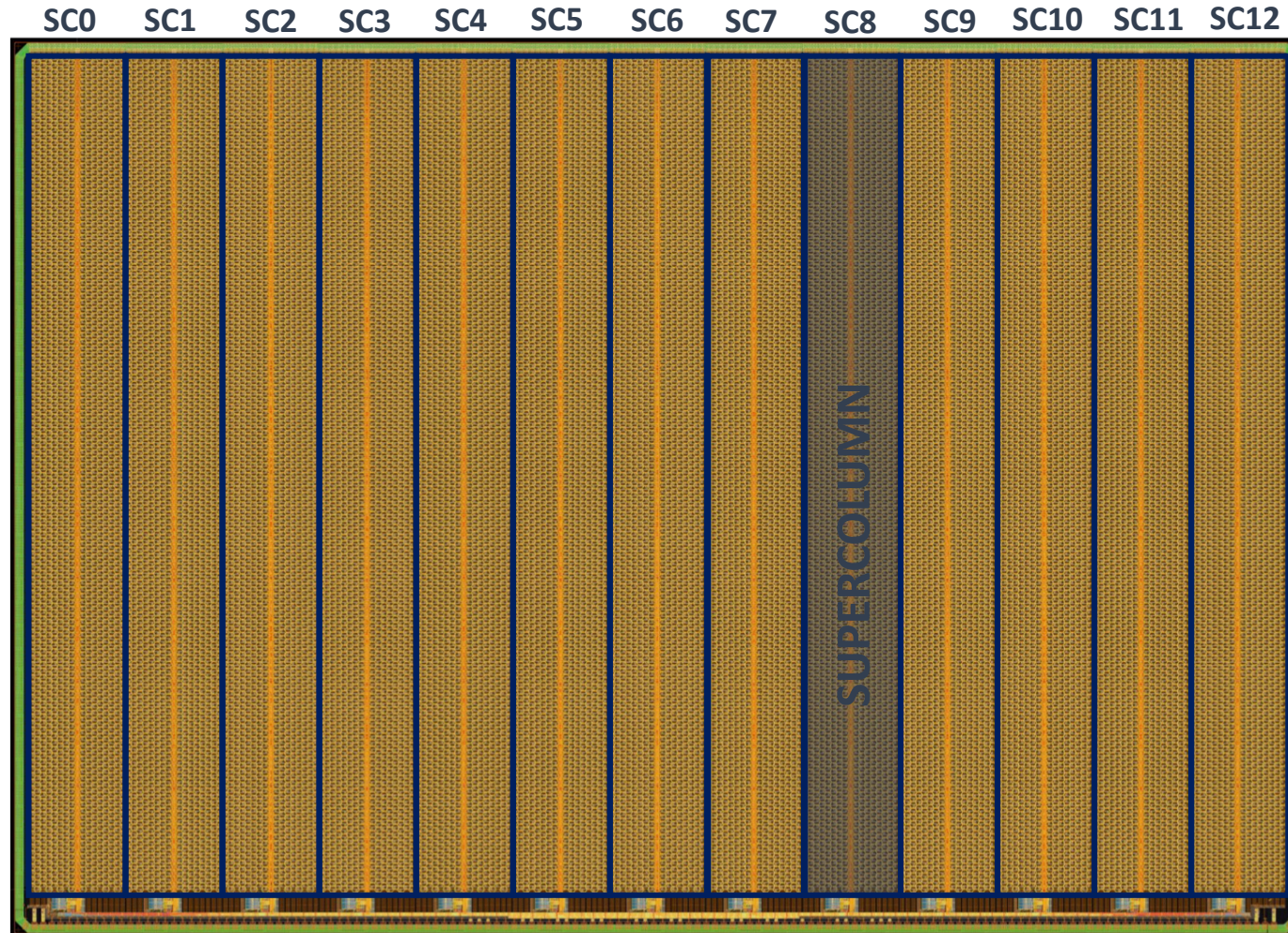
- Chip size: 2.2 x 1.5 cm² with matrix of 208x128 pixels (26'624 pixels in total)



Monolithic ASIC Modular Architecture



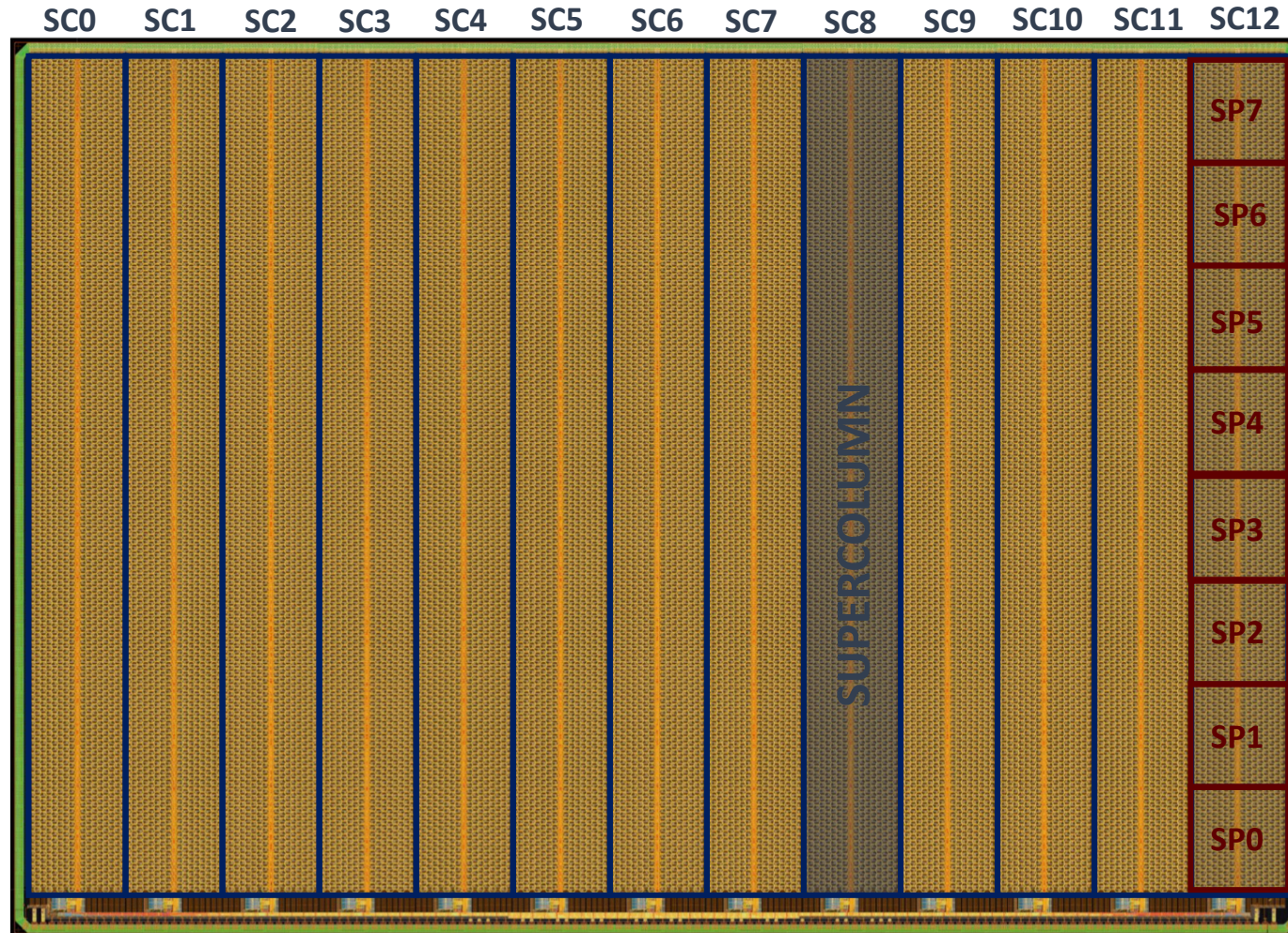
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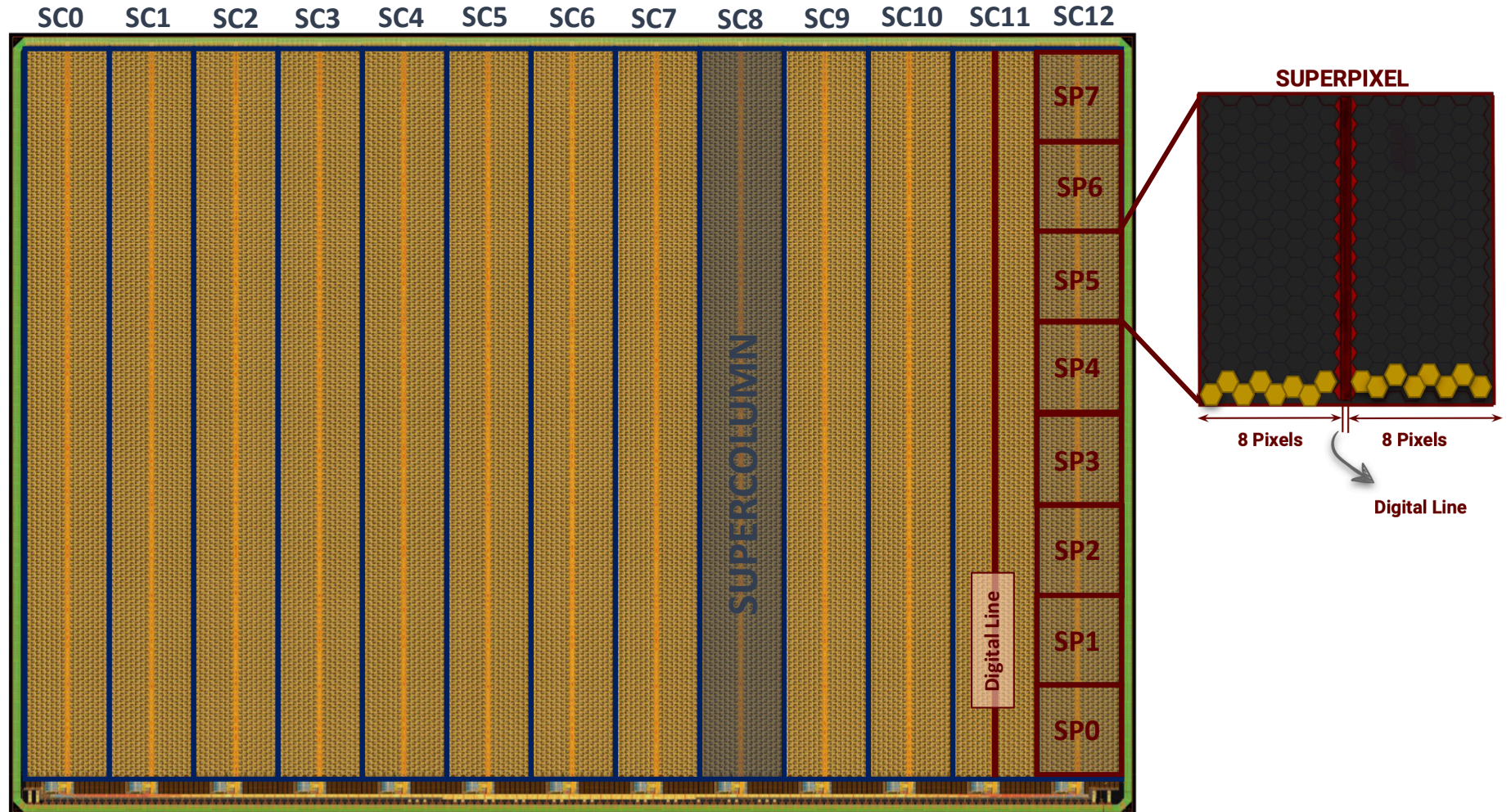
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- Each Supercolumn has 8 **Superpixels** (SP) (16x16 pixels)



Monolithic ASIC Modular Architecture



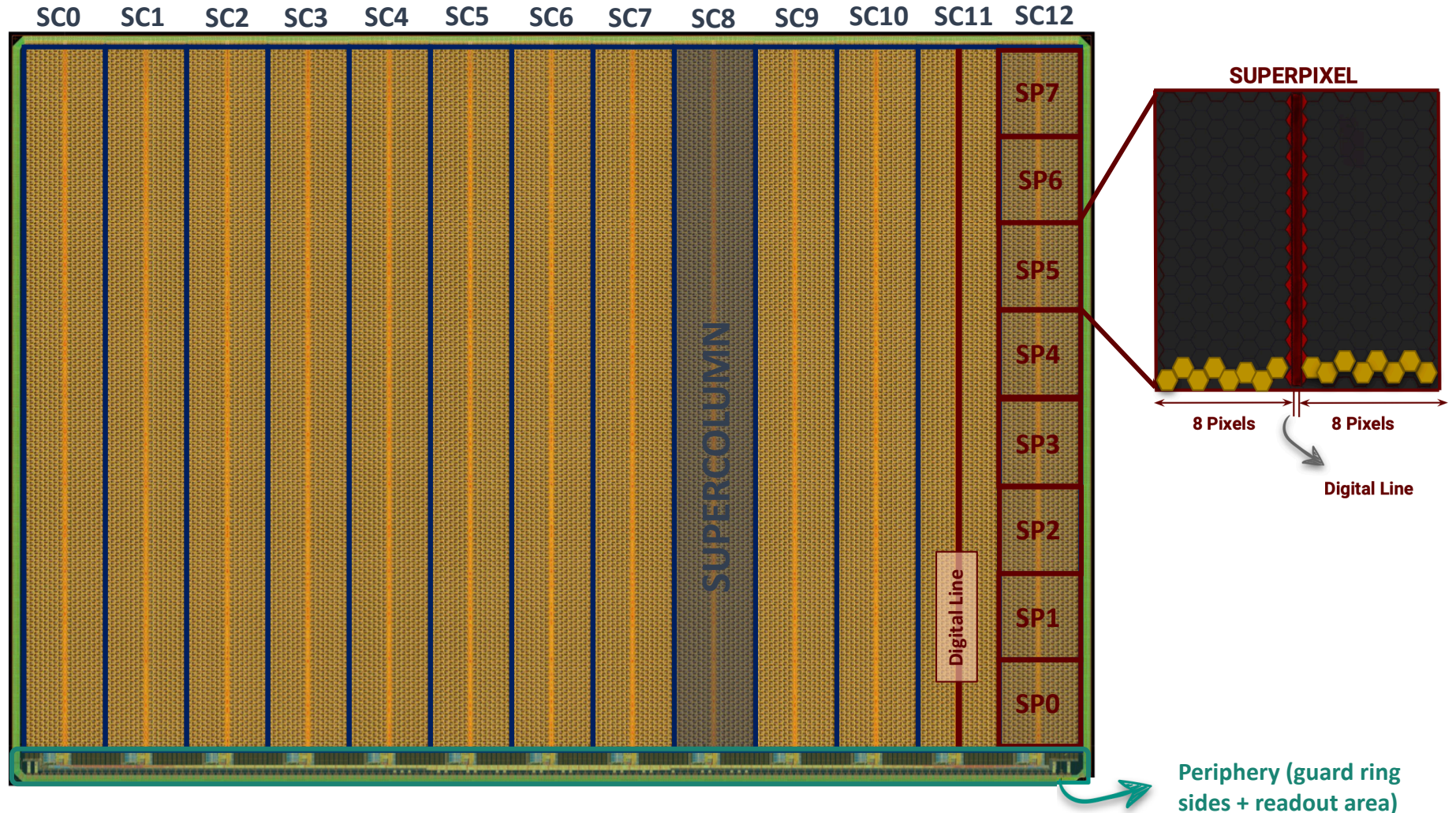
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- and 1 **Digital Line** (40 μm)



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- 13 Supercolumns (SC)
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- and 1 **Digital Line** (40 μm)
- **Periphery** (I/O and arbitrary logic) with dead area
 - 720 μm on the readout side
 - 270 μm for the guard ring

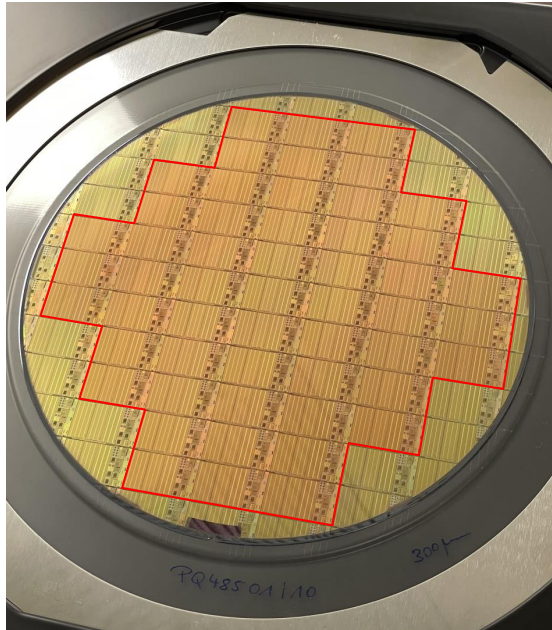


The Pre-production ASIC

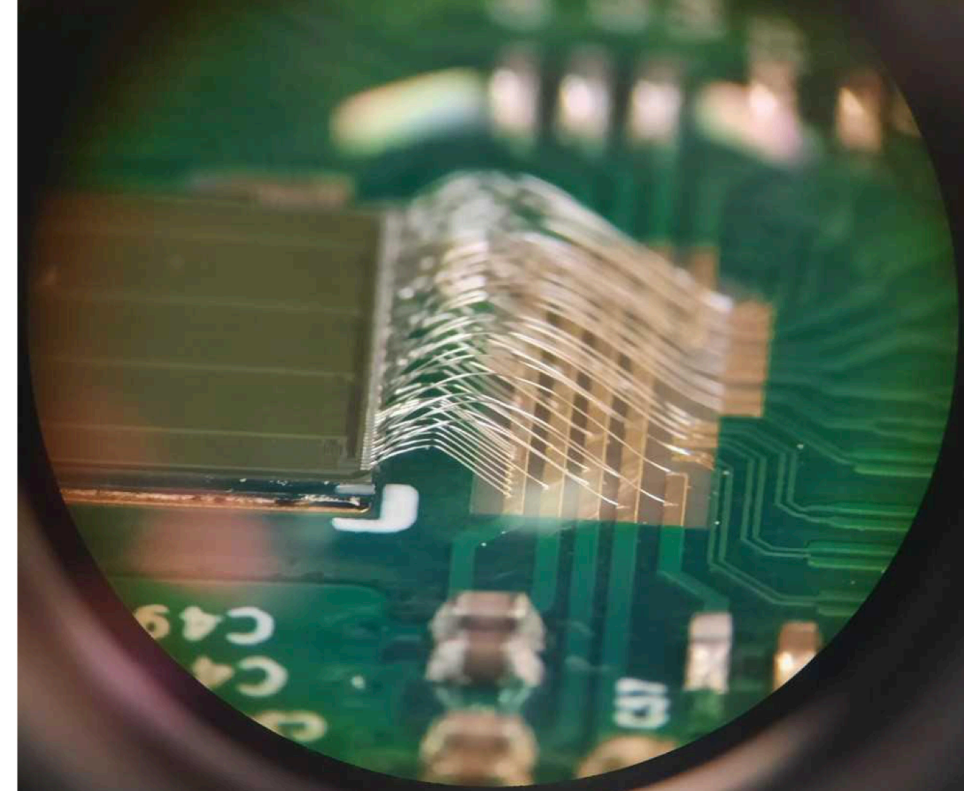
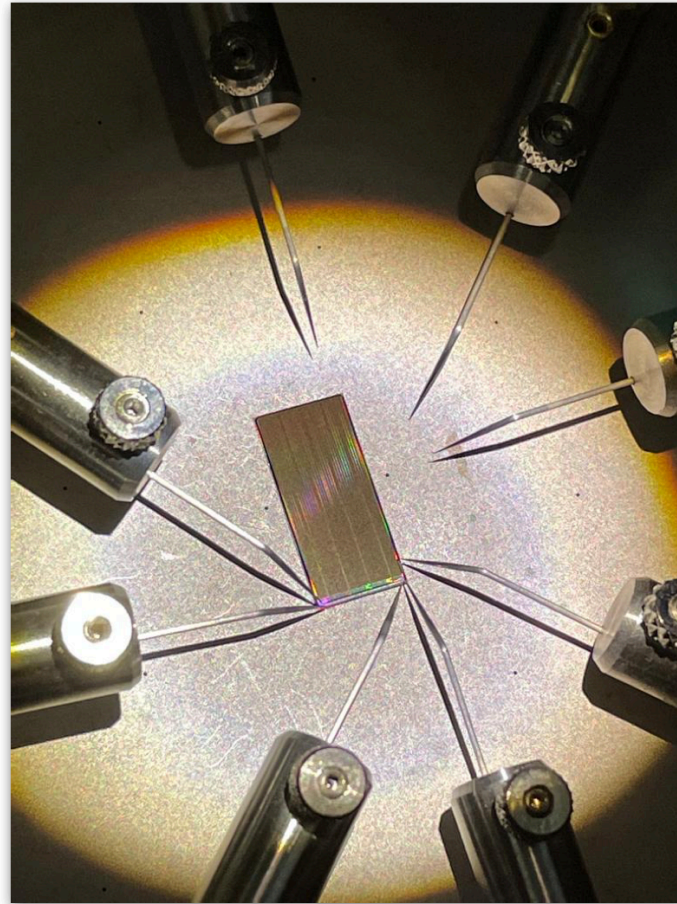
Reticle: 2.4 x 1.5 cm²

53 reticles per wafer

Thickness 300 μm

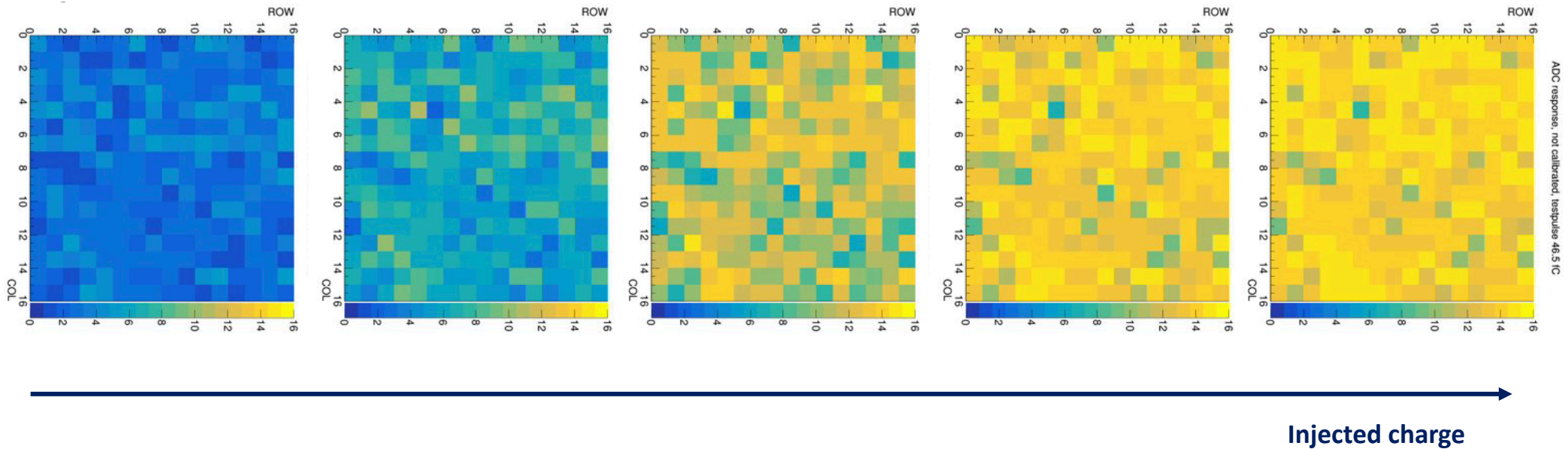


CHIP @ probe station

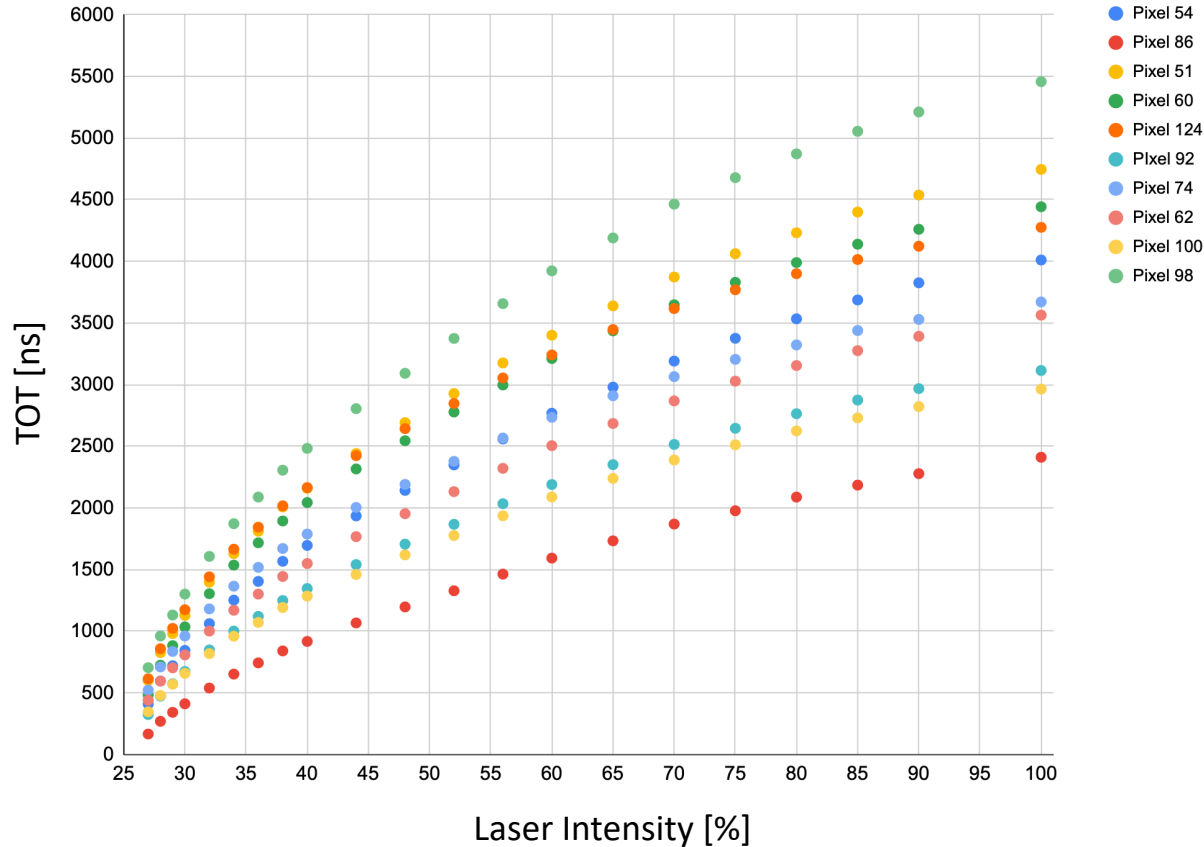


Test on pre-production ASIC: ADC Response

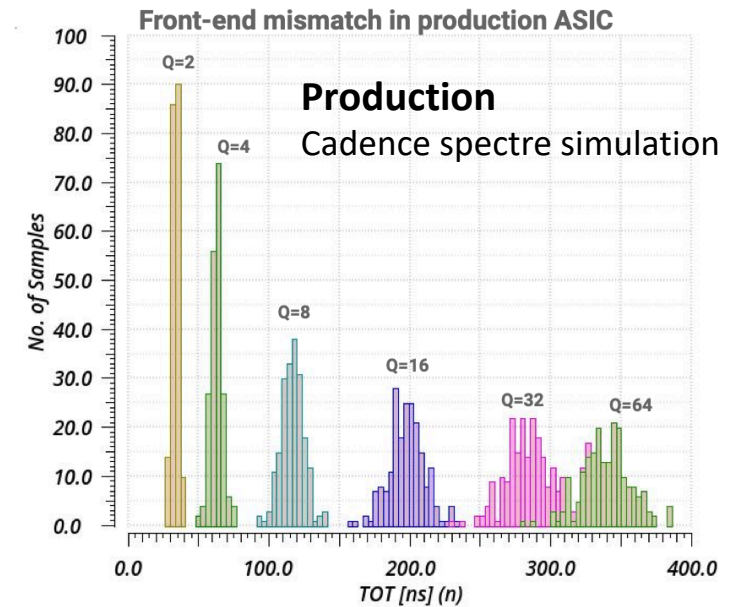
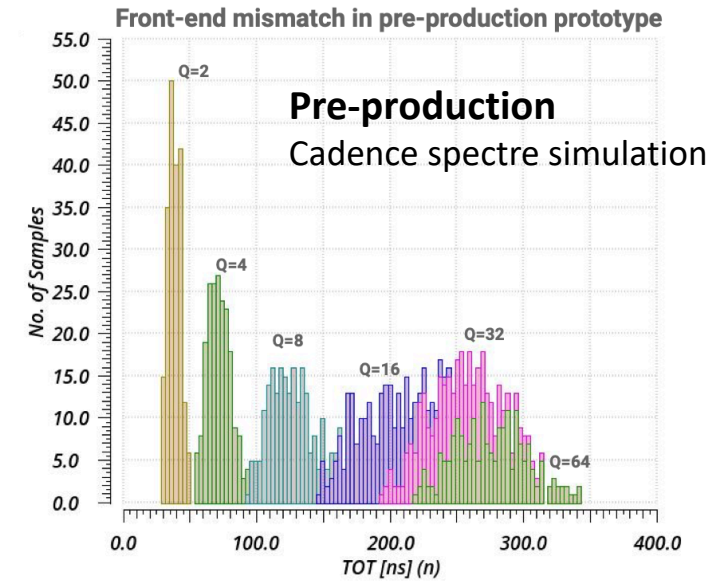
Study of the chip response for different value of injected charge
(here one Superpixel)



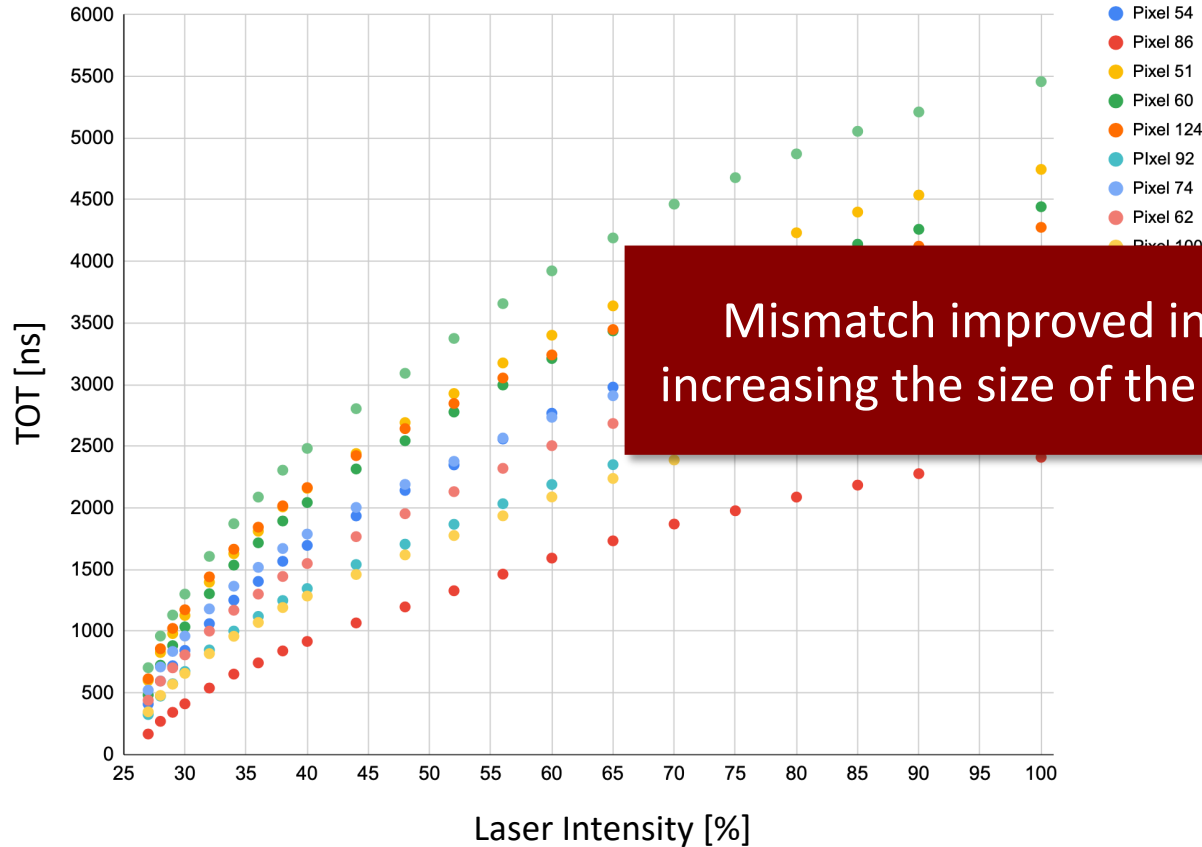
Test on pre-production ASIC Front-end Mismatch



**Large mismatch on the pre-production chip
from amplifier response**

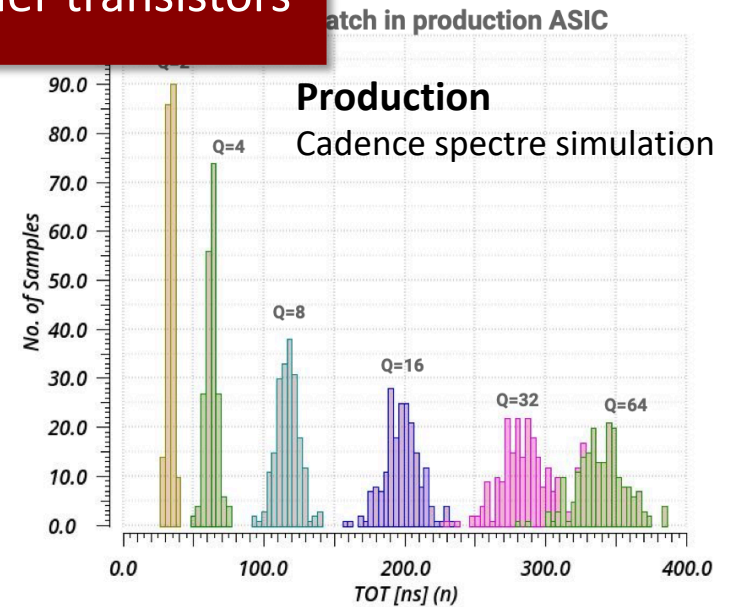
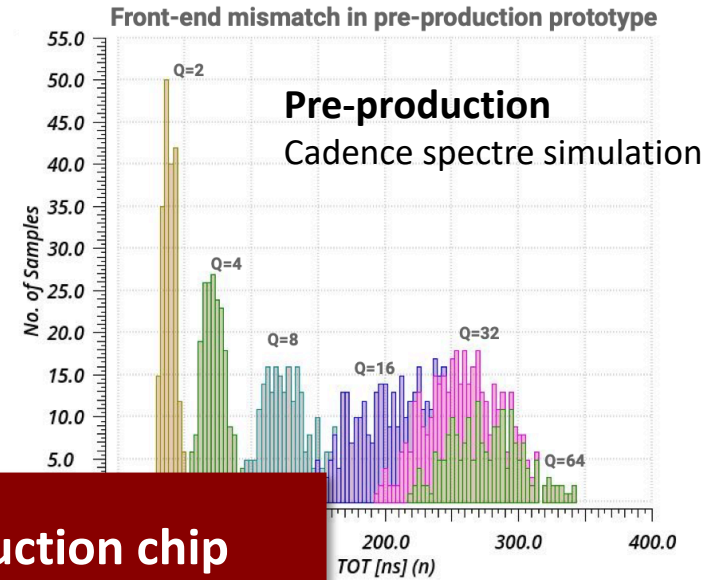


Test on pre-production ASIC: Front-end Mismatch



Mismatch improved in the **production chip** increasing the size of the preamplifier transistors

Large mismatch on the pre-production chip from amplifier response



Summary and Conclusions

- A **new preshower detector** is being developed for the **FASER experiment** at the LHC
 - Enabling the discrimination of ultra-collimated TeV diphoton events from LLP decays
 - 130 nm SiGe BiCMOS Technology MAPS designed and developed at the University of Geneva, with support from KIT and CERN
 - Targeting installation in 2024 and data-taking during last year of LHC Run 3 and HL-LHC



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 - Everything is working fine and we are finalizing the characterization in the Lab
 - Minor bugs have been identified and corrections have been implemented in the production chip
 - First assembled modules currently ongoing
 - A paper on the characterization of the pre-production chip will be published soon

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 - A paper on the characterization of the pre-production chip will be published soon
- **Final production chip submitted in May 2023**
 - Expected delivery: December 2023
 - Test beam at SPS (CERN) planned for August 2024

The FASER Collaboration



FASER Collaboration Members

Henso Abreu (Technion), John Anders (CERN), Claire Antel (Geneva), Akitaka Ariga (Chiba/Bern), Tomoko Ariga (Kyushu), Jeremy Atkinson (Bern), Florian Bernlochner (Bonn), Tobias Boeckh (Bonn), Jamie Boyd (CERN), Lydia Brenner (NIKHEF), Franck Cadoux (Geneva), Roberto Cardella (Geneva), Dave Casper (UC Irvine), Charlotte Cavanagh (Liverpool), Xin Chen (Tsinghua), Andrea Coccaro (INFN), Sergey Dmitrievsky (JINR), Monica D'Onofrio (Liverpool), Yannick Favre (Geneva), Deion Fellers (Oregon), Jonathan Feng (UC Irvine), Carlo Alberto Fenoglio (Geneva), Didier Ferrere (Geneva), Stephen Gibson (Royal Holloway), Sergio Gonzalez-Sevilla (Geneva), Yuri Gornushkin (JINR), Yotam Granov (Technion), Carl Gwilliam (Liverpool), Daiki Hayakawa (Chiba), Shih-Chieh Hsu (Washington), Zhen Hu (Tsinghua), Peppe Iacobucci (Geneva), Tomohiro Inada (Tsinghua), Luca Iodice (Geneva), Sune Jakobsen (CERN), Hans Joos (CERN), Enrique Kajomovitz (Technion), Hiroaki Kawahara (Kyushu), Alex Keykan (Royal Holloway), Felix Kling (DESY), Daniela Köck (Oregon), Umut Kose (CERN), Rafaella Eleni Kotitsa (Geneva), Susanne Kuehn (CERN), Thanushan Kugathasan (Geneva), Helena Lefebvre (Royal Holloway), Lorne Levinson (Weizmann), Ke Li (Washington), Jinfeng Liu (Tsinghua), Jack MacDonald (Mainz), Chiara Magliocca (Geneva), Josh McFayden (Sussex), Andrea Pizarro Medina (Geneva), Matteo Milanesio (Geneva), Theo Moretti (Geneva), Mitsuhiro Nakamura (Nagoya), Toshiyuki Nakano (Nagoya), Friedemann Neuhaus (Mainz), Laurie Nevey (Royal Holloway), Ken Ohashi (Bern), Hidetoshi Otono (Kyushu), Lorenzo Paolozzi (Geneva), Hao Pang (Tsinghua), Brian Petersen (CERN), Markus Prim (Bonn), Michaela Queitsch-Maitland (Manchester), Hiroki Rokujo (Nagoya), Elisa Ruiz Choliz (Mainz), Jorge Sabater-Iglesias (Geneva), Osamu Sato (Nagoya), Paola Scampolì (Bern), Kristof Schmieden (Mainz), Matthias Schott (Mainz), Anna Sfyrła (Geneva), Savannah Shively (UC Irvine), Yosuke Takubo (KEK), Noshin Tarannum (Geneva), Ondrej Theiner (Geneva), Eric Torrence (Oregon), Svetlana Vasina (JINR), Benedikt Vormvald (CERN), Di Wang (Tsinghua), Eli Welch (UC Irvine), Stefano Zambito (Geneva)

The development and construction of the W-Si pre-shower of the FASER experiment was funded by the **Swiss National Science Foundation (SNSF)** under the **FLARE grant 20FL21-201474** at the University of Geneva. Additional financial contributions from **KEK, Kyushu University, Mainz University, Tsinghua University** and the **Heising-Simons Foundation** are also acknowledged



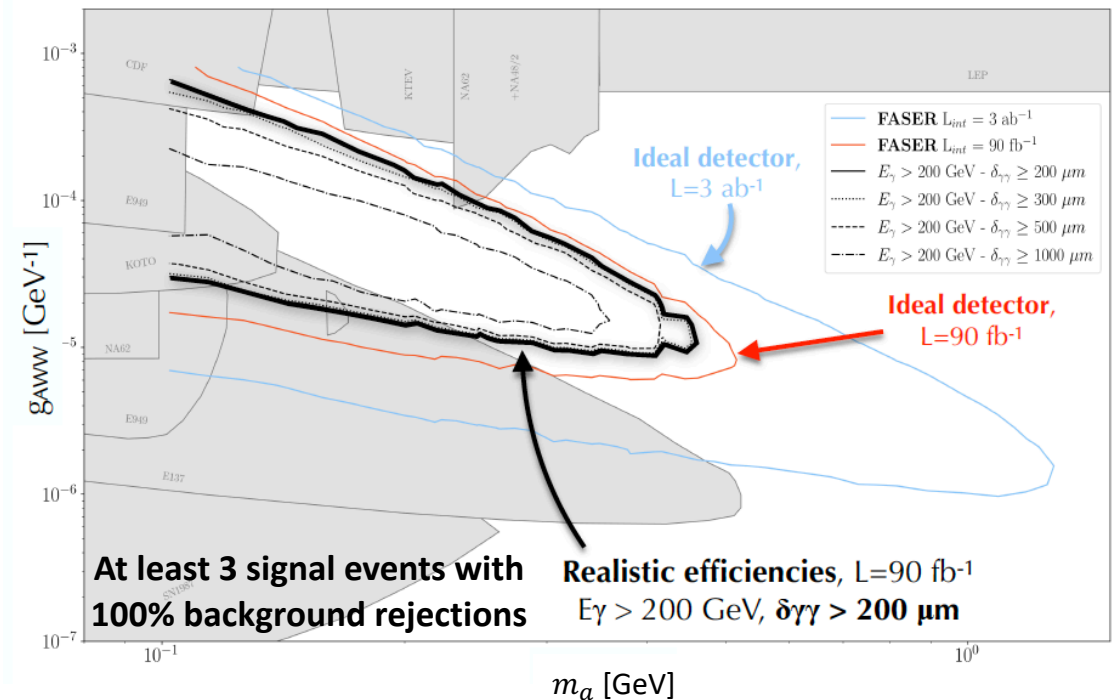
Thank you !

Chiara Magliocca
chiara.magliocca@unige.ch

List of publications on the Preshower Upgrade:

- The FASER Detector
[arXiv: 2207.11427](https://arxiv.org/abs/2207.11427): Accepted for publication in JINST
- The FASER W-Si High Precision Preshower Technical Proposal
[CERN-LHCC-2022-006](https://cds.cern.ch/record/2811111/files/CERN-LHCC-2022-006)
- Measurements and analysis of different front-end configurations for monolithic SiGe BiCMOS pixel detectors for HEP applications
[F. Martinelli et al 2021 JINST 16 P12038](https://arxiv.org/abs/2108.08087)

Discovery potential for ALP

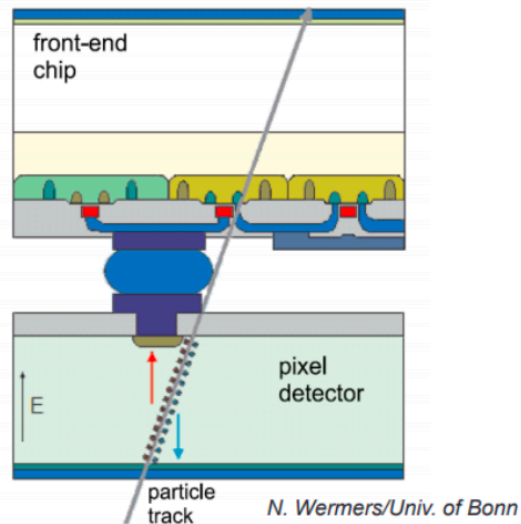


BACKUP SLIDES

Hybrid VS Monolithic Pixel Detectors

ATLAS

Hybrid Pixel Detector



cost ratio

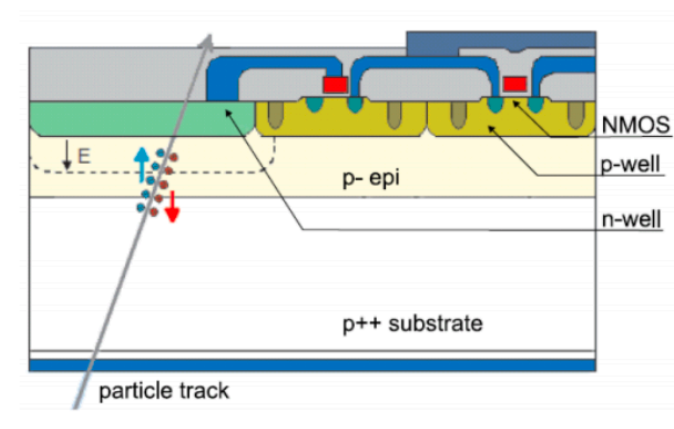
Readout chip : sensor chip : bump bonding \cong 1:2:7

PROS: better optimization of sensors and electronics

CONS: generally high production costs

FASER

Monolithic Pixel Detector (example)

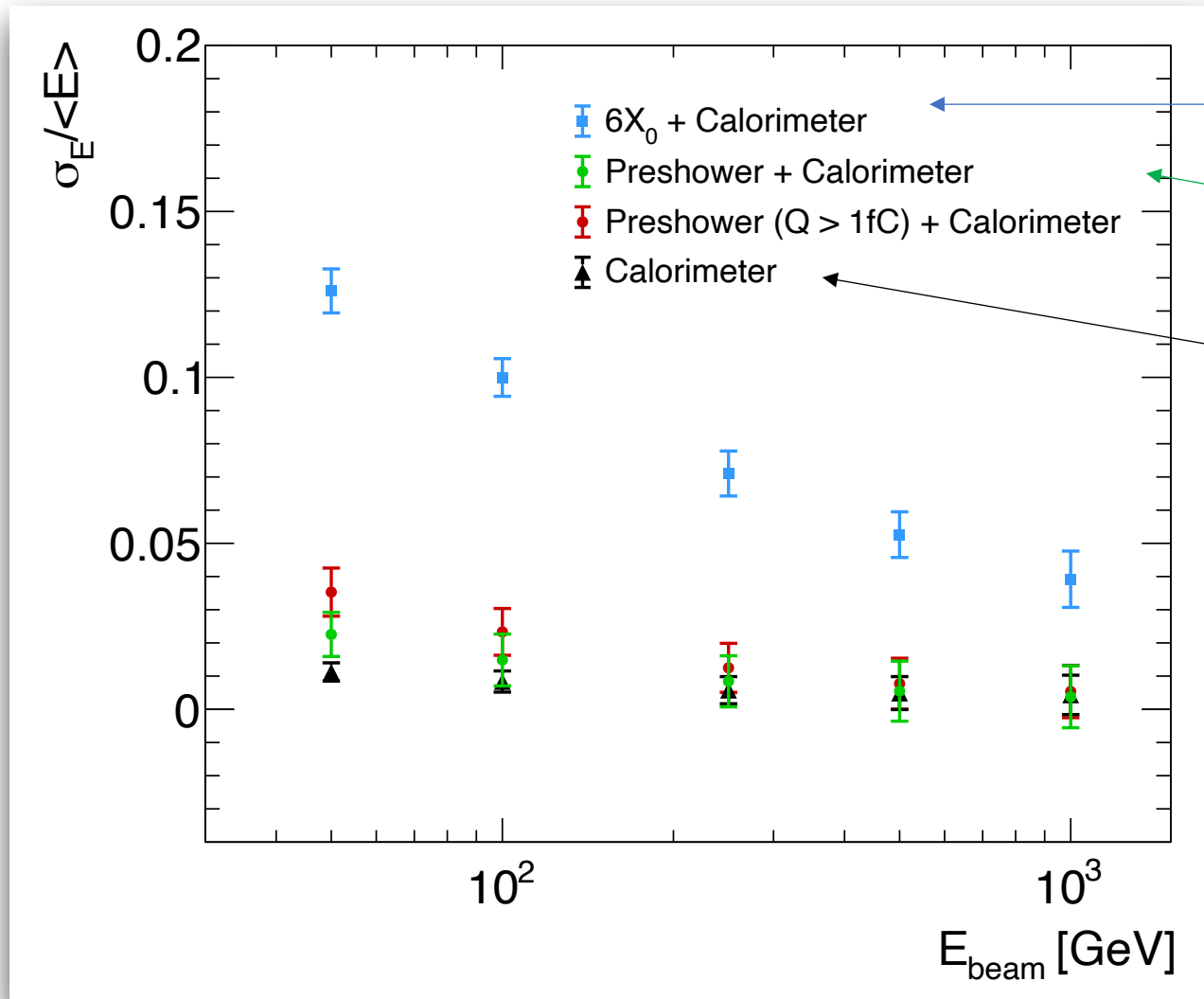


Sensor integrated in the readout, **only CMOS processing**

PROS: lower production costs

CONS: more difficult design

Energy resolution



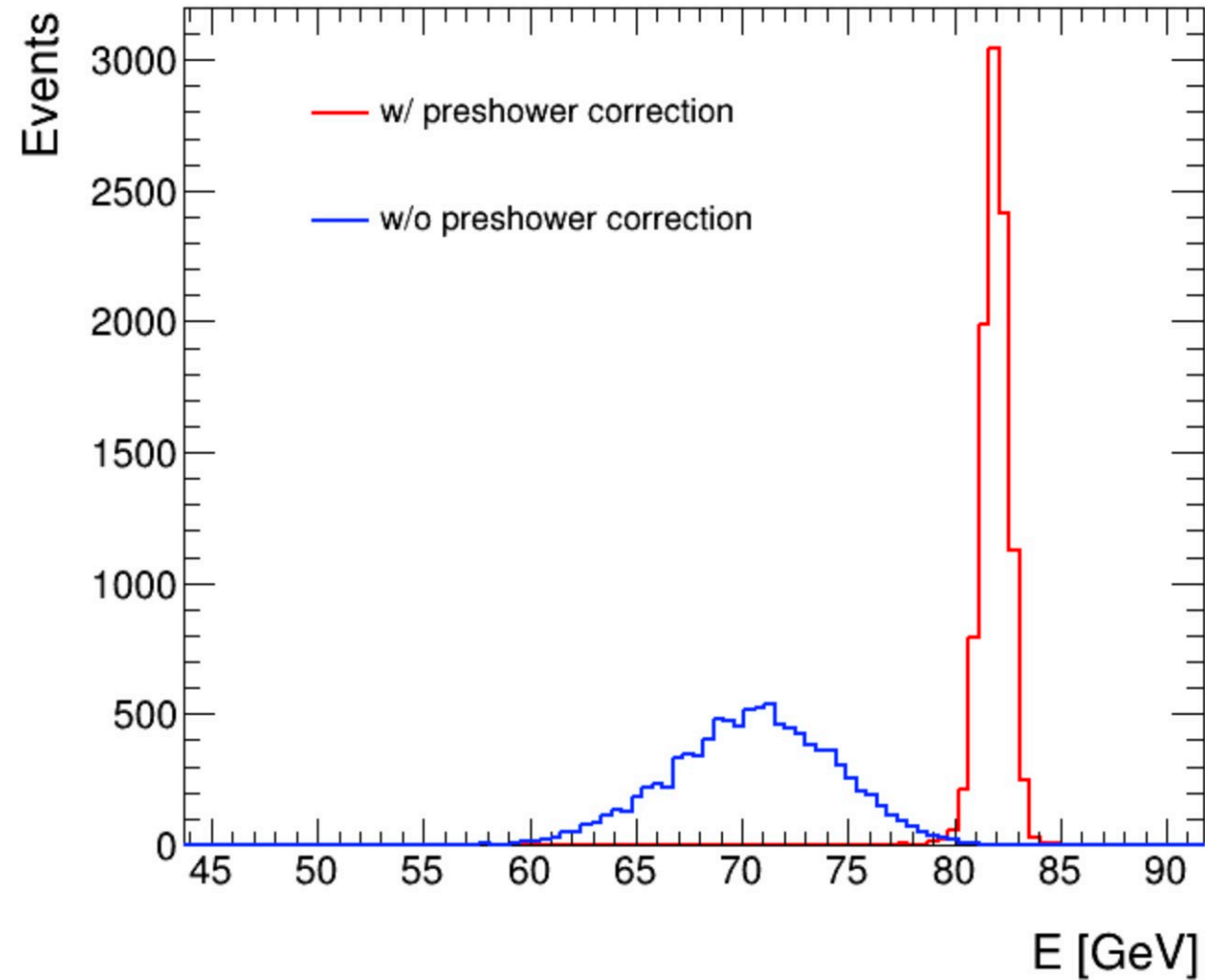
Only looking at the calorimeter
(not using the preshower information)

Correcting with the Preshower
measurement

Calorimeter only

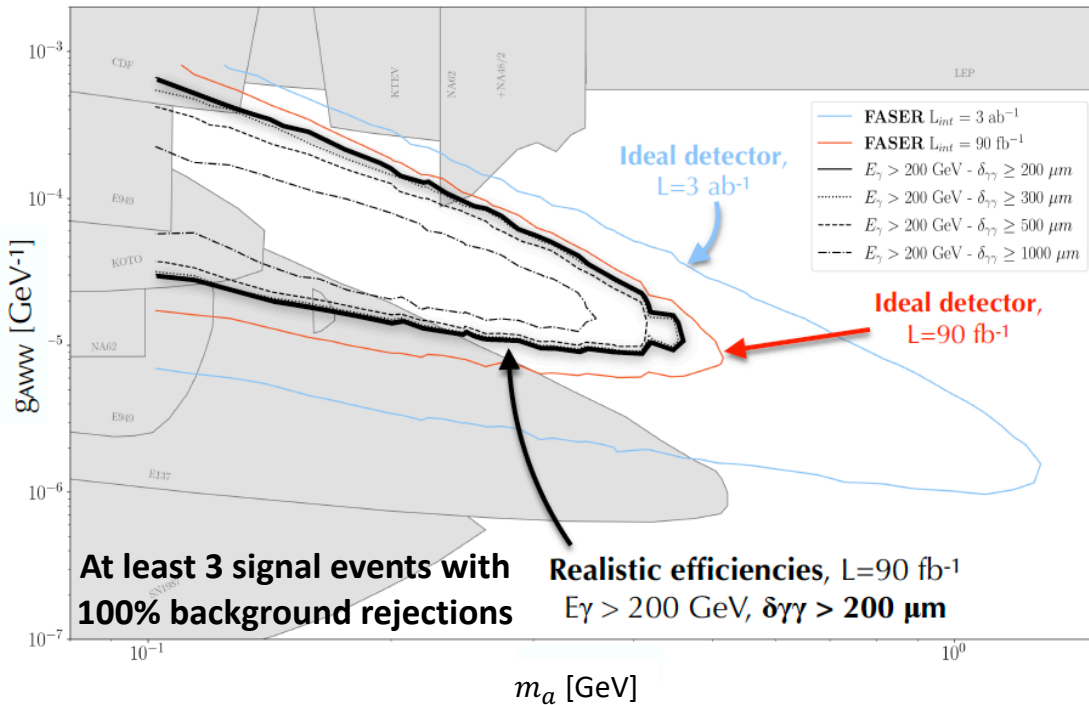
Energy resolution

For 500 GeV photons



Motivations for a new pre-shower detector

Discovery potential for ALP



- **Enables measurements:**

- Axion-Like-Particles (ALP) produced via aWW coupling
- LLP with neutral pions in the final state
- Neutrino background suppression

- **Reinforces measurement:**

- Dark photon and other LLPs decaying into charged fermions
- LLP with charge and neutral pions in the final state

Detector requirement:
 Discriminate photons down to **200 μm separation** to exploit the full potential of the experiment

The FASER Small Prototype Chip (2021)

Purpose

study **different level of INTEGRATION OF THE FRONT-END** electronics inside the sensitive area of the pixels

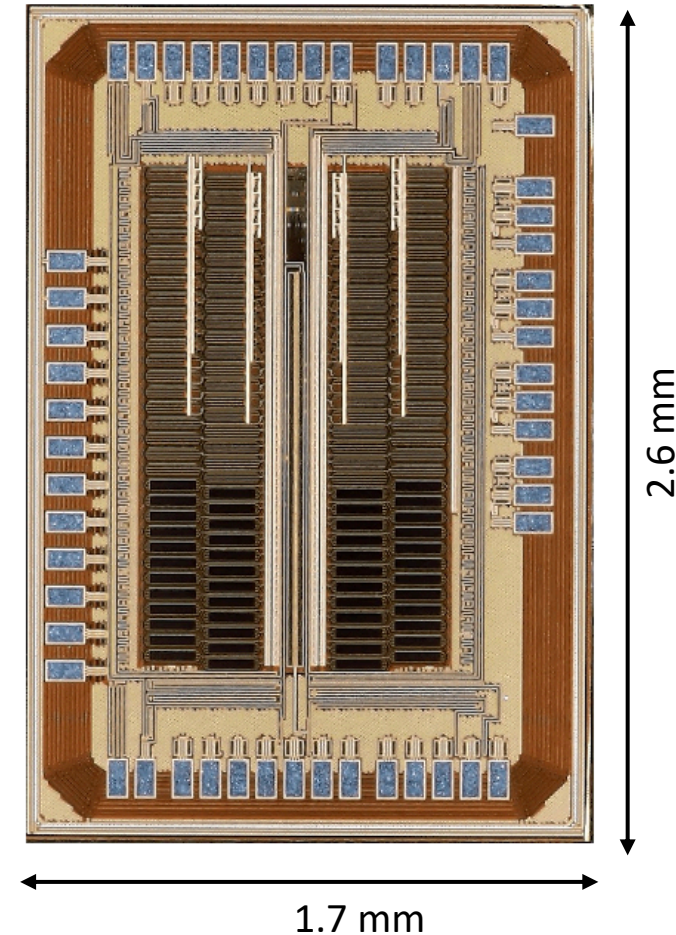
Final aim

identify the BEST FRONT-END CONFIGURATION for the pre-production chip of the FASER Pre-shower (submitted in June 2021)

200 μm x 50 μm PIXELS

shape to reduce the electric field at the edge of the sensitive areas

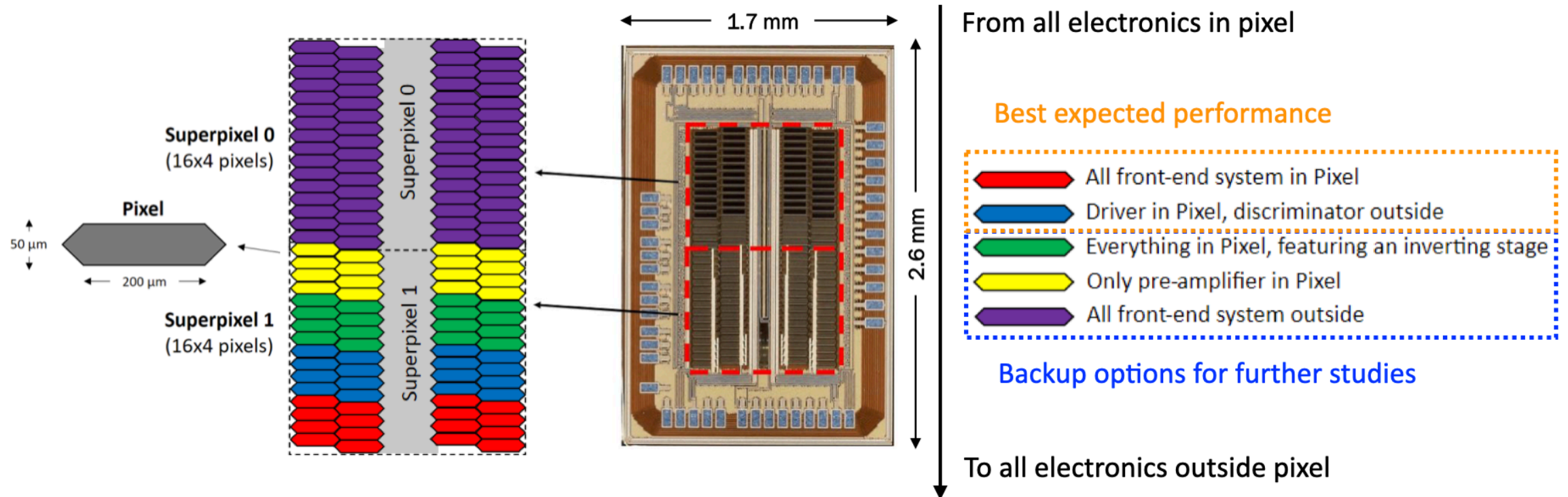
Tested in 2021
2 superpixels
16x4 pixels each



Small Prototype: Front-end Configurations






First chip prototype tested in 2021

- designed to study different levels of integration of the front-end electronics
- simultaneous goals: minimize dead area and routing capacitance, maximize stability



Small Prototype: Results and Comments

F. Martinelli et al.
2021 *J. Inst.* **16** P12038
<https://doi.org/10.1088/1748-0221/16/12/P12038>

-  All front-end system in Pixel
-  Driver in Pixel, discriminator outside
-  Everything in Pixel, featuring an inverting stage.
-  Only pre-amplifier in Pixel
-  All front-end system outside

Configuration	σ_v [mV]	G_c [mV/fC]	ENC [e^-]	$\sigma_{V_{th}}$ [mV]
All f.e. outside pixel	4.2 ± 0.2	159 ± 1.0	165 ± 9	32.3
Only pre-amp. in pixel	2.5 ± 0.1	96.8 ± 0.5	161 ± 9	26.9
All f.e. in pixel, inv. stage	6.9 ± 0.5	179 ± 1.0	241 ± 19	30.8
Pre-amp. and driver in pixel	3.8 ± 0.2	133.7 ± 0.6	178 ± 9	23.4
All f.e. in pixel	5.4 ± 0.4	148 ± 1.0	228 ± 20	27.1

Last two configurations represent a good compromise between *compactness* and *performance*: adopted for the pre-production prototype

Pre-production Chip (2022)

Engineering run (IHP Microelectronics)

In each reticle three pixel matrices

FASER_v1 (baseline)

- 4 supercolumns
- in-pixel preamplifier and driver
- discriminator outside

FASER_v2

- 128 x 48 pixels
- 3 supercolumns
- all in-pixel (preamplifier, driver and discriminator)

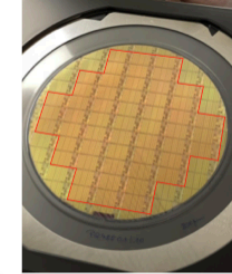
FASER_ALT

- 128 x 48 pixels
- 3 supercolumns
- no analog memories
- counter for charge measurement

Reticle: 2.4 x 1.5 cm²

53 reticles per wafer

Thickness 300 μm

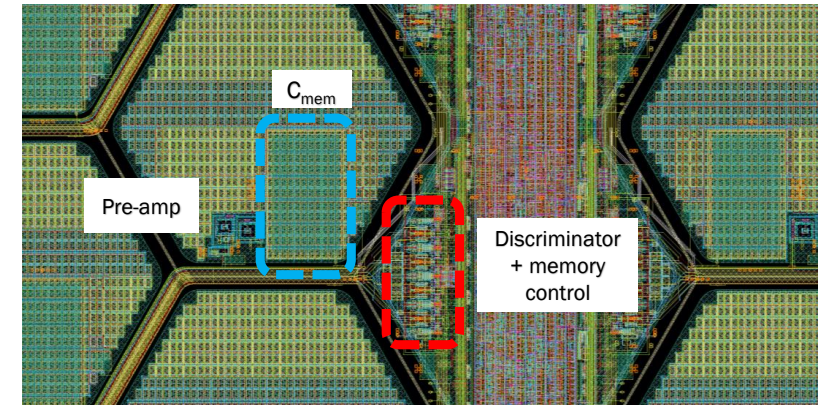
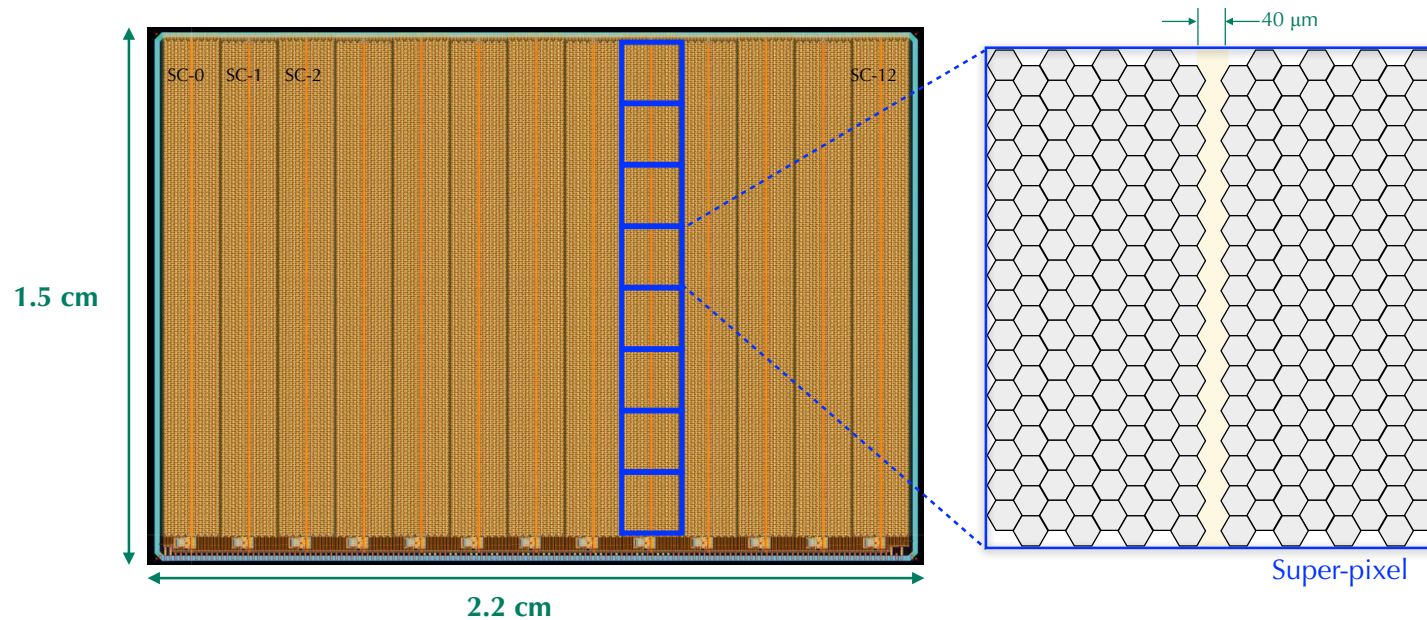


Pre-production Chip (2022)

Chip organized in 13 **Supercolumns**, each with

- Active region, subdivided into 8 **Superpixels** of 16x16 pixels each
- Digital column (40 μm) in the middle: sharing of digital electronics

Digital periphery on the bottom, and multiple guard-ring structures

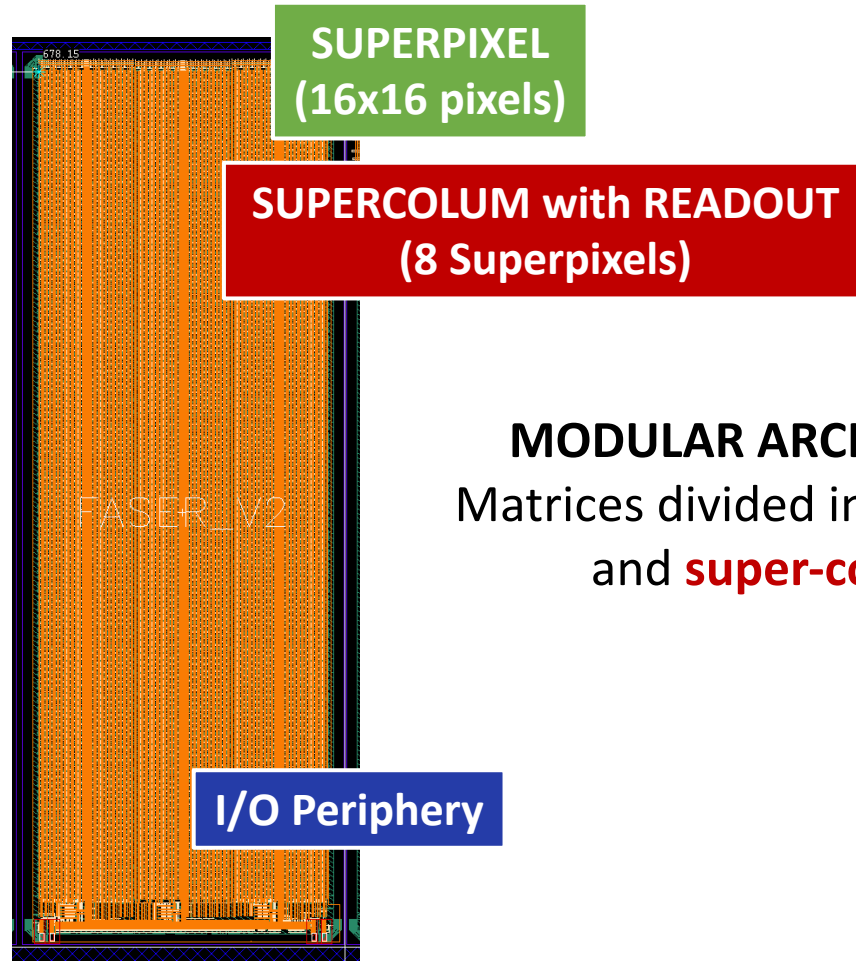


Superpixel:

- 16 rows of 8+8 pixels
- Analog multiplexer
- 4-bit flash ADC
- 3 FAST-OR lines
- Local bias circuit
- Programming logic to mask pixels

Dead area <5%

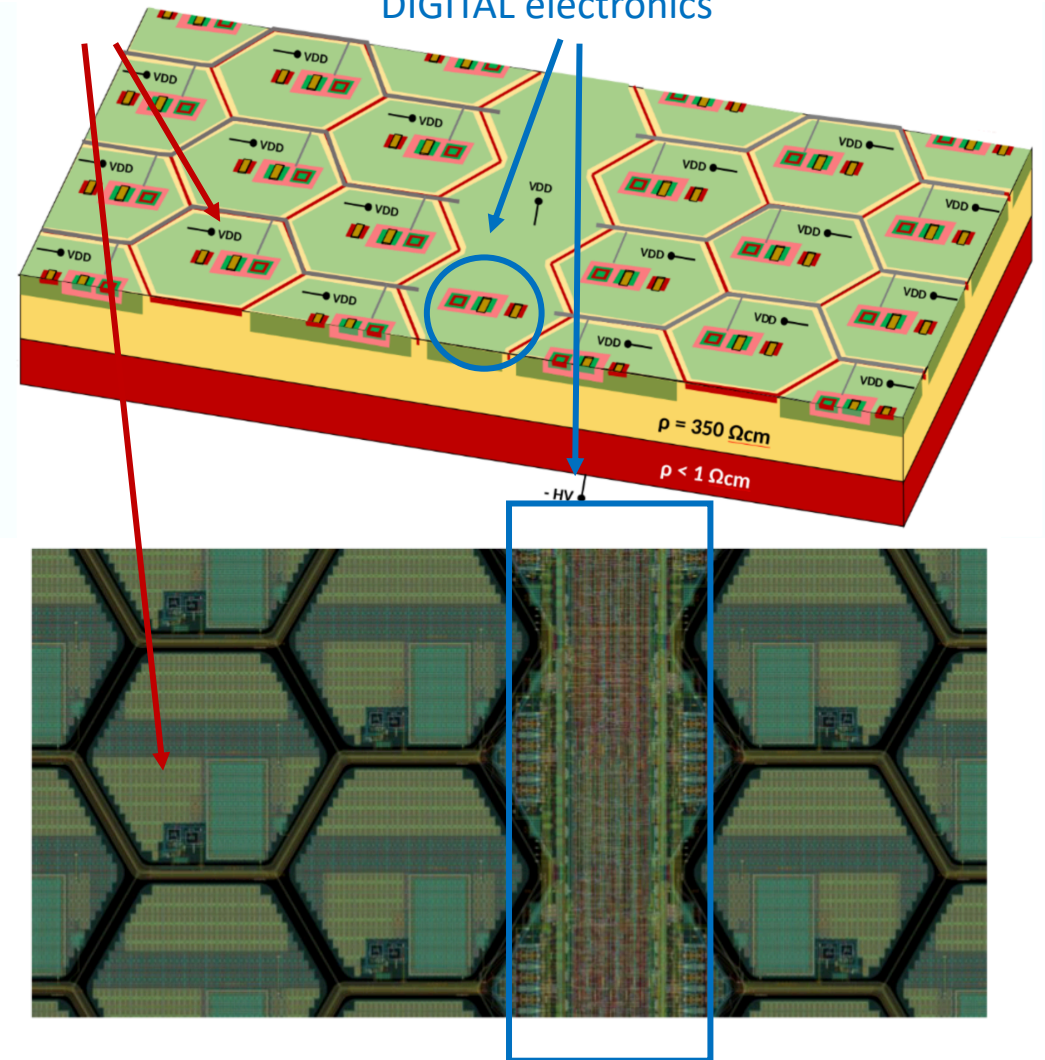
The Chip Architecture



MODULAR ARCHITECTURE
Matrices divided in **super-pixels**
and **super-columns**

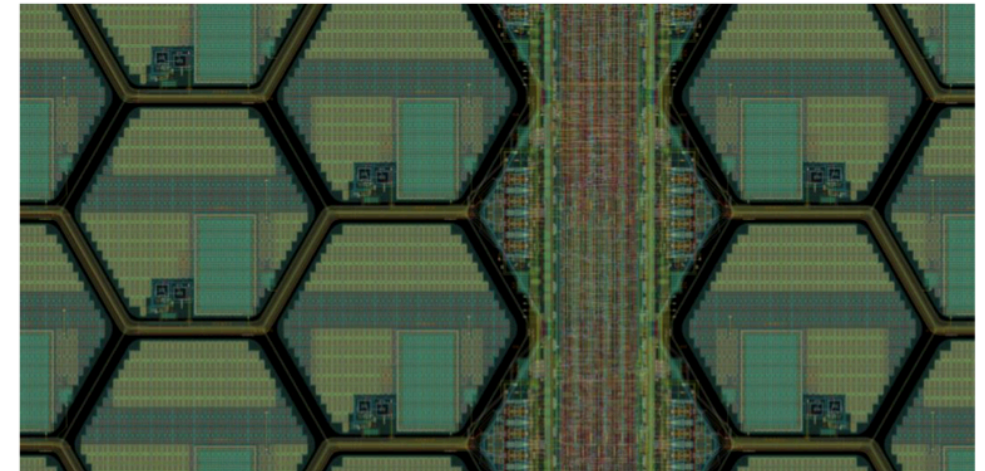
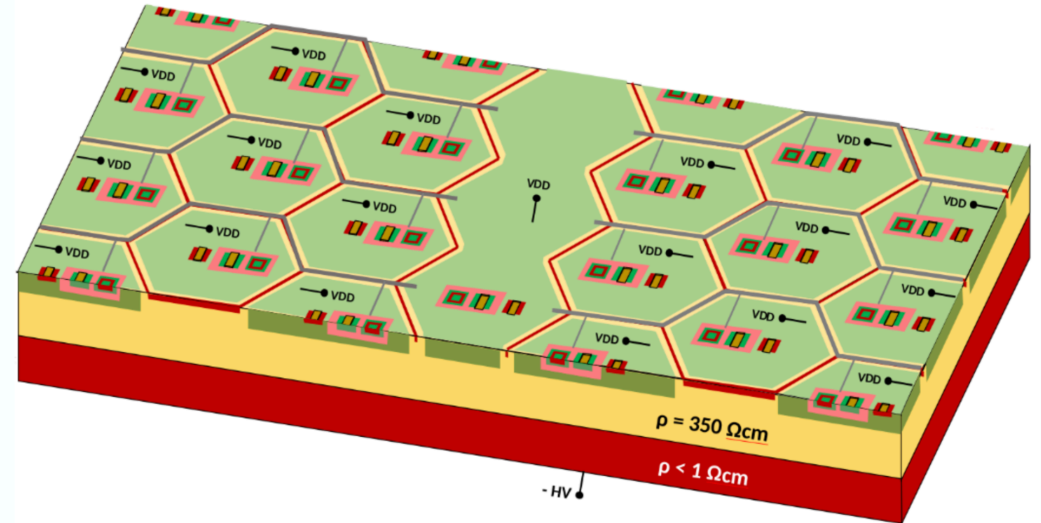
ANALOG electronics

DIGITAL electronics



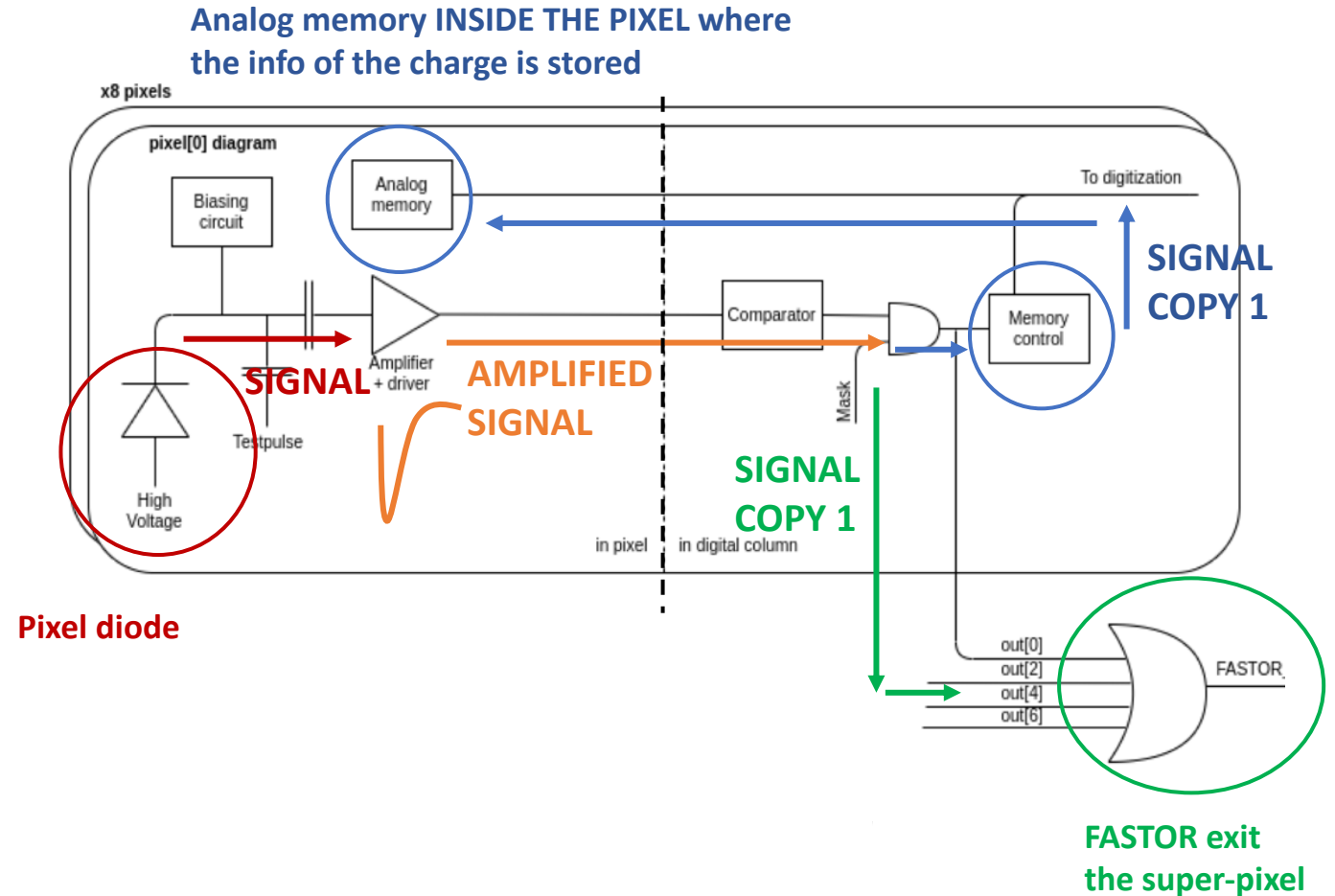
Sensor Cross Section

- Low resistivity heavily p-doped substrate as a support
- Negative high voltage applied to the substrate
- High resistivity 50 μm epitaxial layer
- Triple – well design
- **Analog electronics inside the pixel**
- **Digital electronics outside the pixel**
- Electronics inside the guard ring isolated from substrate using a deep n-well
- Digital electronics in a separate well
- Positive low voltage applied to pixels and electronics deep n-wells
- $\approx 6\%$ dead area in the pixel matrix

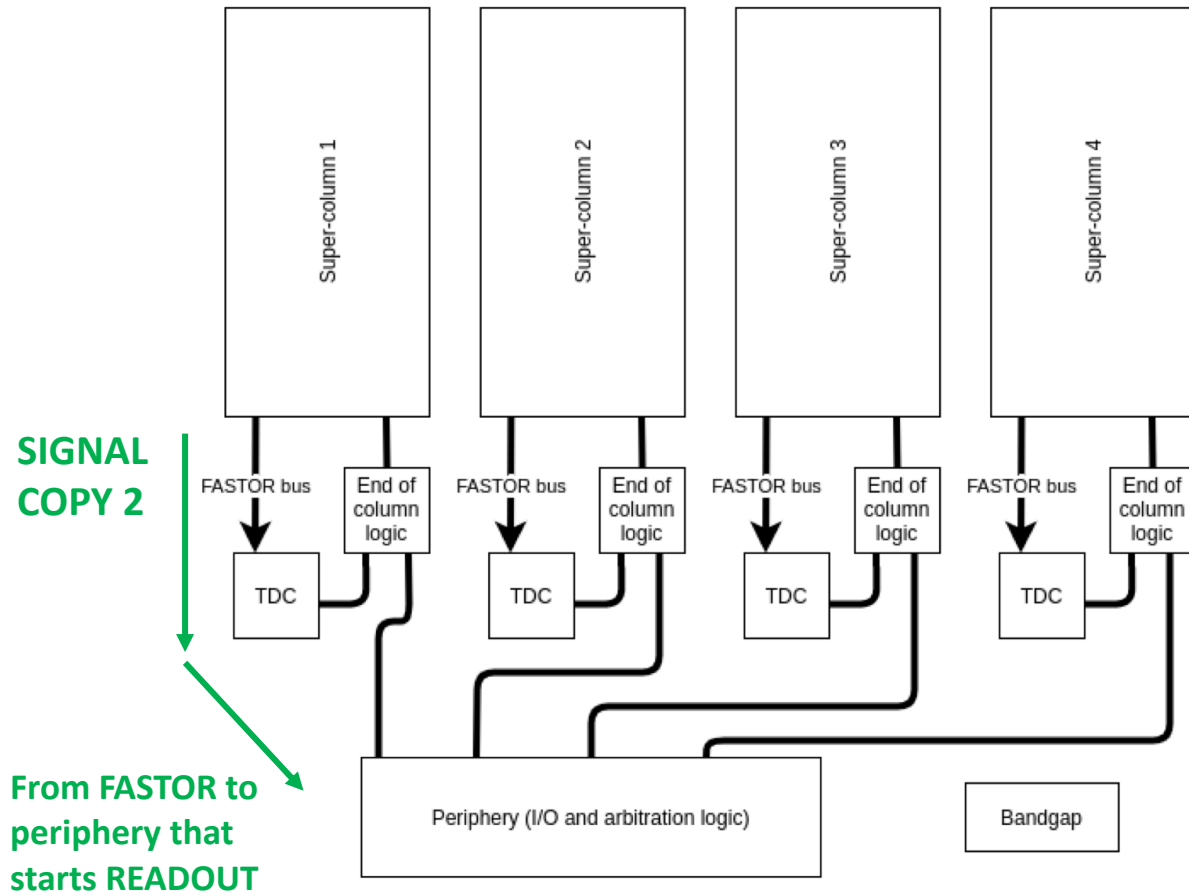


Monolithic Pixel ASIC: Pixel Circuitry

- When an hit arrives a signal is produced
- The signal gets amplified by the PRE-AMPLIFIER
- The signal is sent outside the pixel to the COMPARATOR
- The output of the comparator is copied:
 - COPY 1 goes to the MEMORY CONTROL
 - COPY 2 goes to the FAST-OR that will give the signal to start the Readout
- Memory Control loads the analog memory inside the pixel if the charge is over threshold
- After some delay, readout starts supercolumn after supercolumn



ASIC Structure and Readout



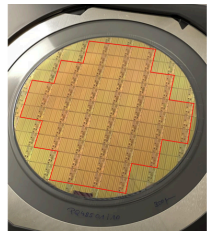
- A copy of the signal exit **IMMEDIATELY** the pixel through the FASTOR
- Each FASTOR send a signal to the periphery to start the READOUT
- To be sure we collected the charge entirely, the **periphery waits a bit before starting the READOUT**
- **Readout time max 200 μ s**
- If in a super-pixel **zero FASTOR** are active, **zero bit** are sent to the periphery (optimization)

Pre-production ASIC Prototype: First Tests

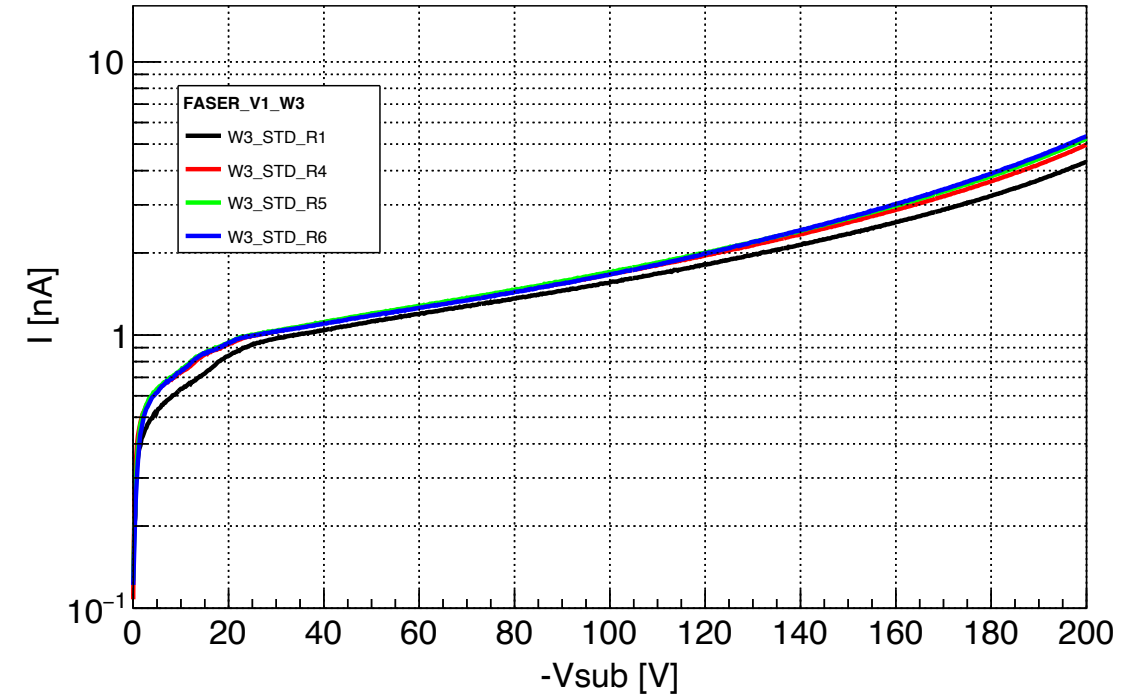
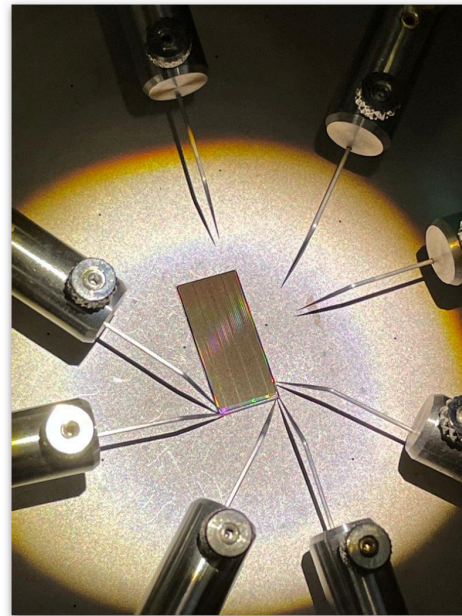
Wafers received in June 2022, tested in the laboratory

- I-V characteristics measured at probe station
- Charge response scrutinised with ^{109}Cd and IR laser
- Stress-tests for digital electronics and readout

Reticle: 2.4 x 1.5 cm²
53 reticles per wafer
Thickness 300 μm



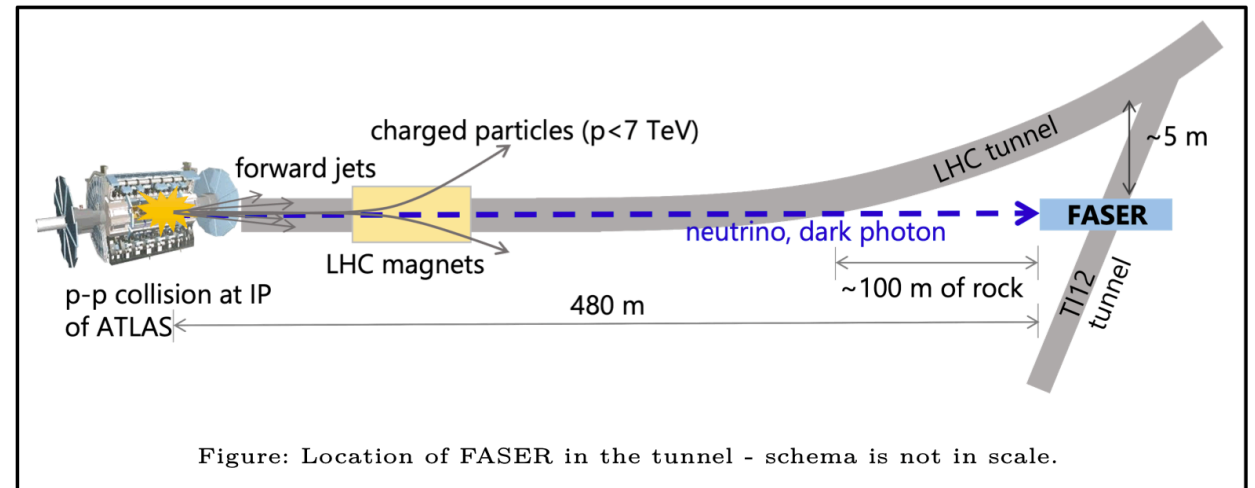
CHIP @ probe station



The chip can operate up to -200 V

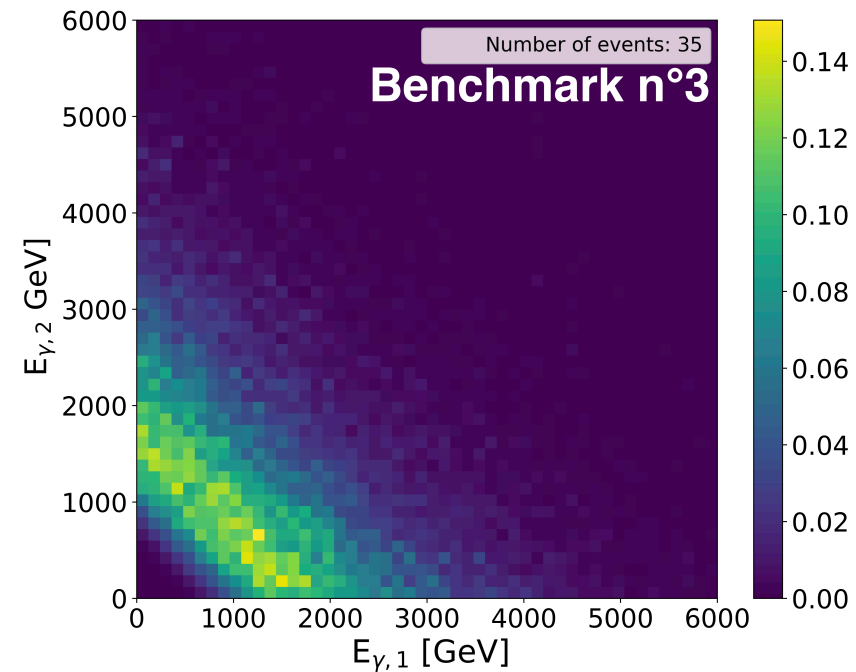
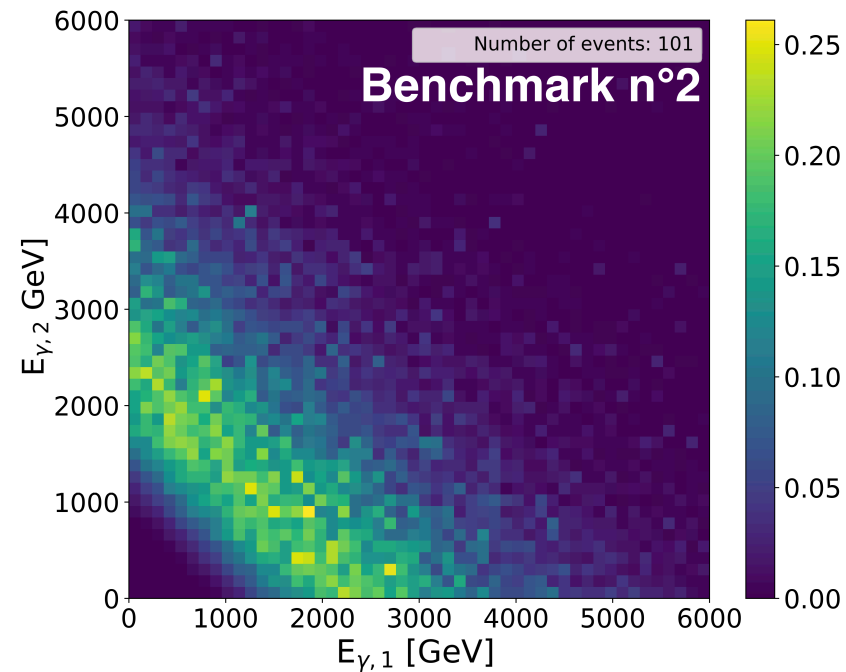
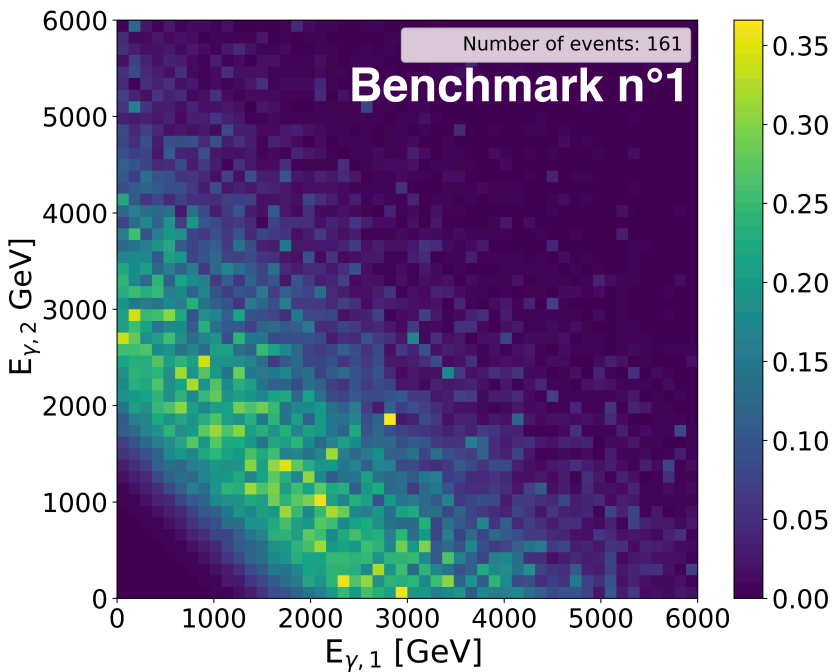
The LHC Forward Physics

- Most LHC detectors sensitive to transverse particles coming from head-on pp collisions
- **Large forward cross section currently wasted and not probed**
- Forward particles are **highly collimated**: only $\sim 1\text{cm}$ spread for 100 m longitudinal travel
- **A small detector far away could potentially see a large flux of Long-Lived Particles (LLPs) with very small background**



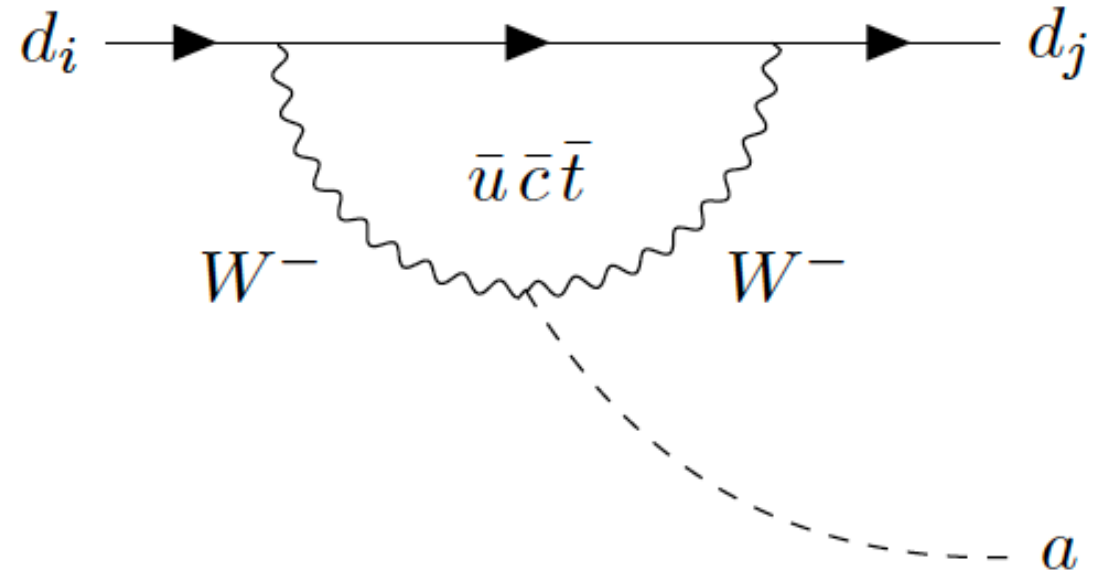
- ForwArd Search ExpeRiment
- Proposal submitted in 2018 and approved by Cern in March 2019

Di-photon Signal Energy Distributions



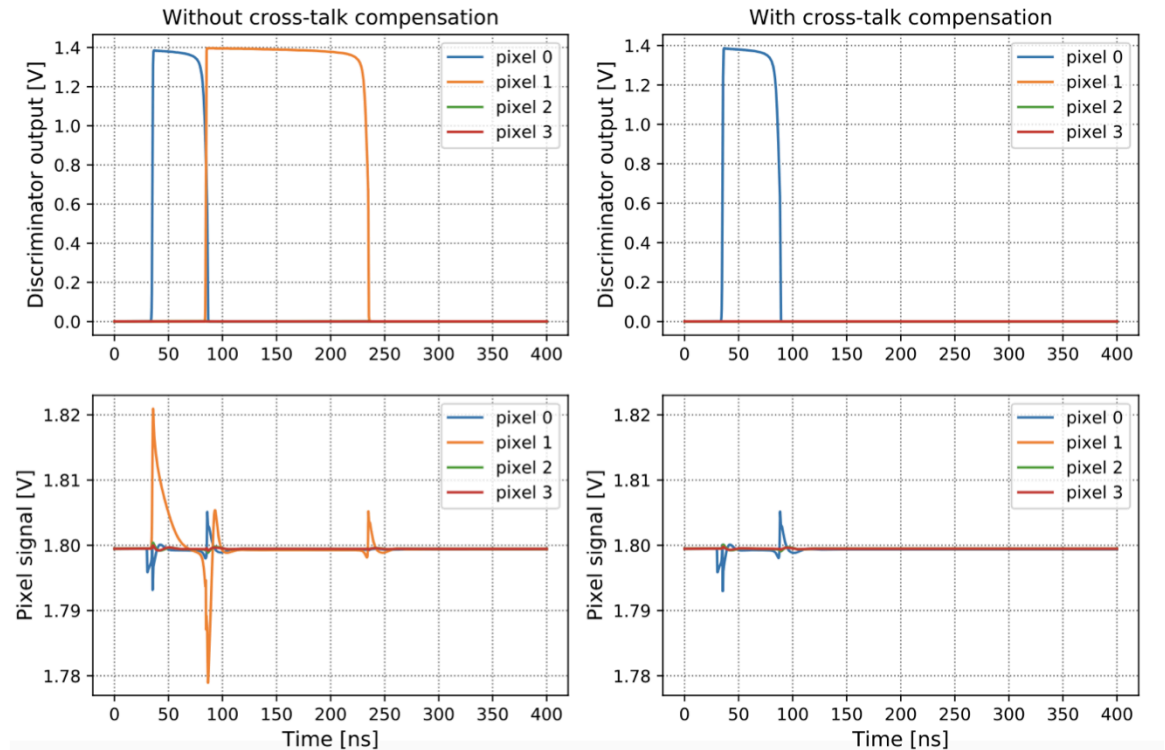
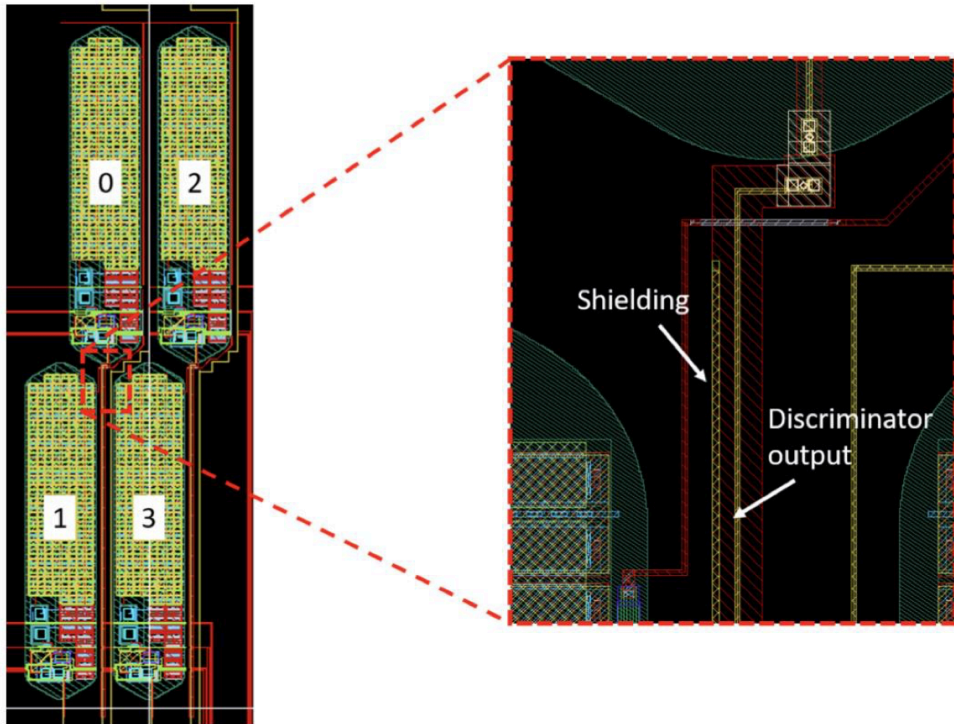
ALPs Production: FCNC

- Down type quark becomes an up type quark
- Emits a charged boson which will itself radiate an ALP
- It then interacts with the up type quark which changes flavor again to become a down type quark



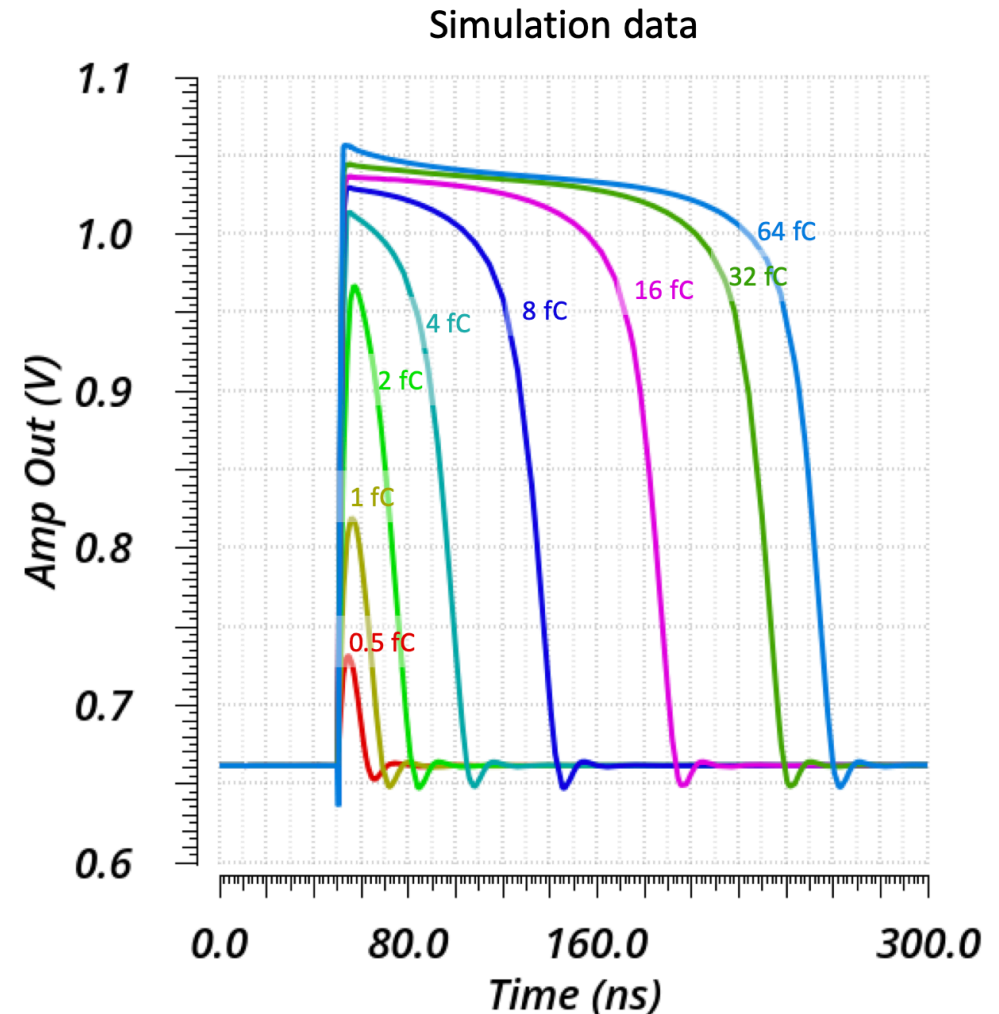
Signal Routing and Crosstalk Suppression

- Signal routed in a **shielded bus** to **minimize crosstalk between neighboring pixels**

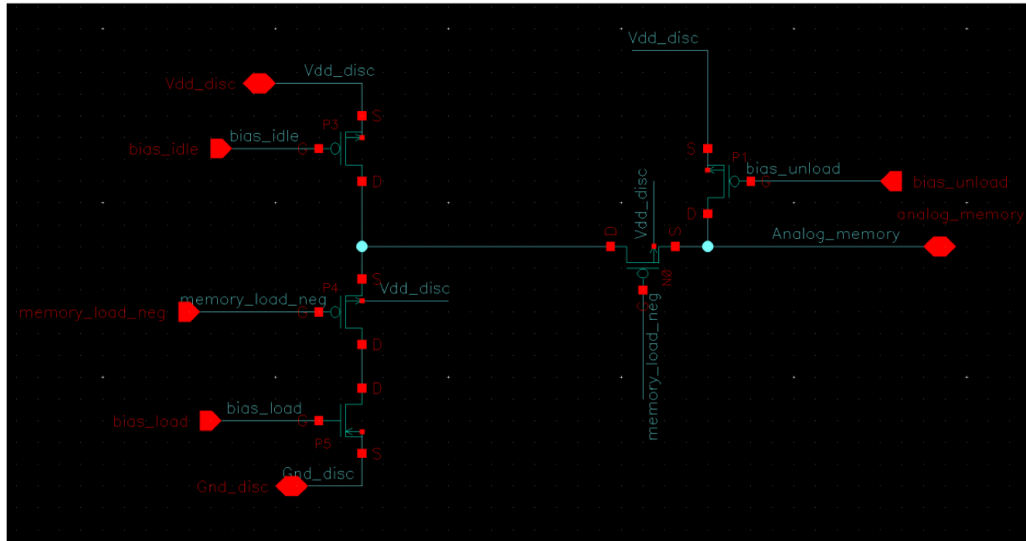


Amplification Stage

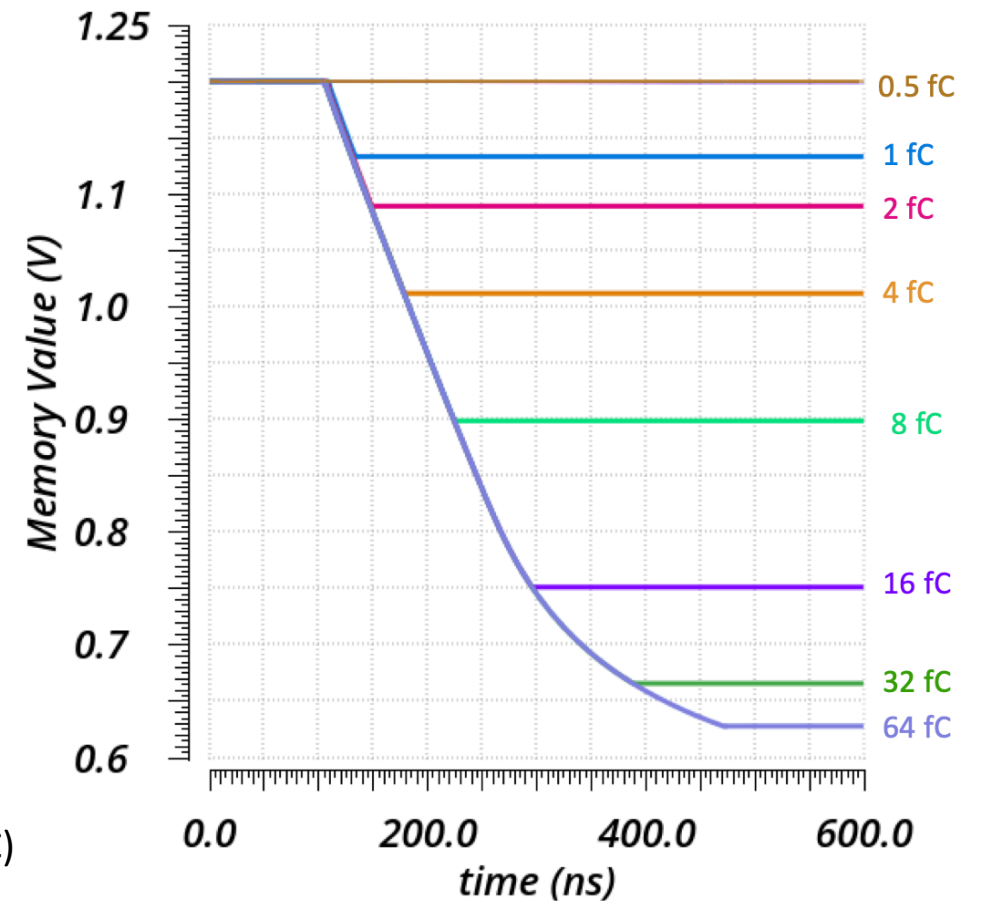
- Since we want to measure high charges we convert the charge information to Time Over Threshold
- For different charges, if the charge increases also the TOT increases but not linearly (almost logarithmic relation)
- Saturation at 64 fC (intrinsic saturation of the pixel)



Memory Control and Analog Memories



- When signal returns below threshold, memory is disconnected and left floating until read by the flash ADC
- Current leakage even if the switch is opened
- It takes 200 μs to degradate the memory value of 30 mV (= 1 bin of our ADC)



After 200 μs we still measure something but we are less precise

Di-Photon Reconstruction Efficiencies

$E_{\gamma 1} = 1 \text{ TeV}$

$E_{\gamma 2} = 1 \text{ TeV}$

